Radiation Report

TPS73801-SEP Total Ionizing Dose (TID) Radiation Report

ABSTRACT

This report covers the radiation characterization results of the TPS73801-SEP low-dropout regulator. The study was done to determine total ionizing dose (TID) effects under low dose rate (LDR) up to 50krad(Si) as a one time characterization. The results show that all samples passed within the specified limits up to 50krad(Si) and radiation lot acceptance testing (RLAT) will be performed using 22 units at 50krad(Si) for future wafer lots. Furthermore, the TPS73801-SEP is packaged in a space enhanced plastic for low outgassing characteristics and is single event latch-up (SEL) immune up to 43MeV-cm^2/mg making the device suitable for low Earth orbit space applications. The device is ideal for clean analog supply conditions. Examples include low noise linear regulator power supply for RF, VCOs, receivers, and amplifiers.

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Trademarks

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1 Device Information

The TPS73801-SEP is a 1A LDO regulator optimized for fast transient response. The device is capable of supplying 1A at a dropout voltage of 300mV. The low operating quiescent current (1mA) drops to less than 1µA in shutdown. In addition to the low quiescent current, the TPS73801-SEP regulator incorporates several protection features which make it ideal for use in battery-powered systems.

1.1 Device Details

Table 1-1 lists the device information used in the initial TID characterization and qualification for LDR.

Table 1-1. Device and Exposure Details

TID LDR Details	
TI Device Number	TPS73801-SEP
Package	6-pin DCQ (SOT-223)
Technology	JI1
Die Lot Number	0025369
A/T Lot Number / Date Code	0646206/06Z736H
Quantity Tested	67 irradiated devices + 3 control
Lot Accept/Reject	Devices passed 3krad(Si), 10krad(Si), 20krad(Si), 30krad(Si), 50krad(Si)
LDR Radiation Facility	Cobham RAD Solutions, Colorado Springs, CO
LDR Dose Level	3krad(Si), 10krad(Si), 20krad(Si), 30krad(Si), 50krad(Si)
LDR Dose Rate	0.01rad(Si)/s
LDR Radiation Source	Gammacell JLSA 81-22 Co-60
Irradiation Temperature	Ambient, room temperature

Figure 1-1. TPS73801-SEP Device Photo

2 Total Dose Test Setup

2.1 Test Overview

The TPS73801-SEP was irradiated at a low dose rate of less than 10mrad(Si)/s. The product was irradiated up to 50krad(Si) and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The device was functional and passed all electrical parametric tests with readings within data sheet electrical specification limits.

2.2 Test Description and Facilities

The TPS73801-SEP LDR exposure was performed on biased and unbiased devices in a Co60 gamma cell under a 10mrad(Si)/s exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10mrad(Si)/s to a maximum of approximately 65rad(Si)/s, determined by the distance from the source. The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry was verified using TLDs prior to the radiation exposures. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments production Automated Test Equipment (ATE). ATE test limits are set per data sheet electrical limits based on initial qualification and characterization data. Post radiation measurements were taken within 30 minutes of removal of the devices form the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

2.3 Test Setup Details

The devices were tested in both biased and unbiased conditions as described below:

2.3.1 Unbiased

For the unbiased conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 shows the bias conditions for each pin during irradiation.

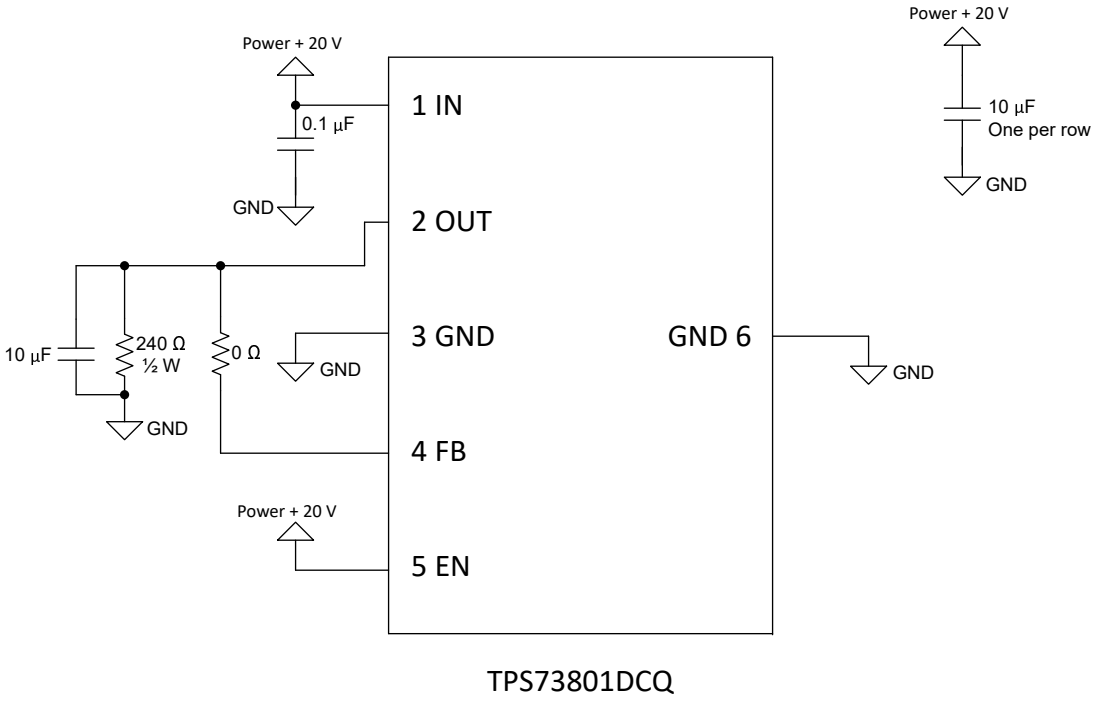


Figure 2-1. TPS73801-SEP Biased Diagram

2.4 Test Configuration and Condition

A step-stress (3k, 10k, 20k, 30k, and 50k) test method was used to determine the TID hardness level. That is, after a predetermined TID level was reached, an electrical test was performed on a given sample of parts to verify that the units are within specified data sheet electrical test limits. From initial feasibility studies the difference between pre- and post-irradiation was greater for samples that were biased, hence for RLAT 22 units were used at the 50krad(Si) dose level with biased setup conditions and this will be repeated for each wafer lot.

Table 2-1 list the serialized samples that was used during the radiation hardness-assured (RHA) characterization.

Table 2-1. LDR 3krad(Si) to 50krad(Si) Biased and Unbiased Device Information

LDR = 10mrad(Si)/s				
Total Samples: 67				
Exposure Levels				
3krad(Si)	10krad(Si)	20krad(Si)	30krad(Si)	50krad(Si)
Biased 1, 2, 3, 4, 5	**Biased** 11, 12, 13, 14, 15	**Biased** 41, 42, 43, 44, 45, 46, 47, 48, 49, 50, 51 , 52, 53, 54, 55, 56, 57, 58, 59, 60, 61, 62	**Biased** 21, 22, 23, 24, 25	**Biased** 31, 32, 33, 34, 35
Unbiased 6, 7, 8, 9, 10	**Unbiased** 16, 17, 18, 19, 20	**Unbiased** 63, 64, 65, 66, 67	**Unbiased** 26, 27, 28, 29, 30	**Unbiased** 36, 37, 38, 39, 40

3 Tested Parameters

Table 3-1 links the test numbers for each test condition with the data sheet parameters.

Table 3-1. TPS73801-SEP Data Sheet Parameters With Test Numbers

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT	Test# or Name
V_{FB} FB pin voltage	Tj = 25°C, V_{IN} = 2.21V, I_{LOAD} = 1mA	1.192	1.21	1.228	V	60.1__VOUT_1MA_VINMIN
	Tj = 25°C, V_{IN} = 20V, I_{LOAD} = 1mA	1.174	1.21	1.246	V	60.2__VOUT_1MA_VINMAX
	Tj = 25°C, V_{IN} = 2.5V, I_{LOAD} = 1mA	1.174	1.21	1.246	V	60.3__VOUT_1mA_VINNOM
	Tj = 25°C, V_{IN} = 2.5V, I_{LOAD} = 1A	1.174	1.21	1.246	V	60.4__VOUT_1A_VINNOM
Line regulation	Tj = 25°C, ΔV_{IN} = 2.21V to 20V, I_{LOAD} = 1mA		1.5	5	mV	60.5__LINE REG
Load regulation	Tj = 25°C, V_{IN} = 2.5V, ΔI_{LOAD} = 1mA to 1A		2	8	mV	60.6__LOAD REG
V_{DO} Dropout voltage V_{IN} = $V_{OUT(NOMINAL)}$	Tj = 25°C, I_{LOAD} = 1mA		0.02	0.06	V	50.1__DROPOUT_1MA
	Tj = 25°C, I_{LOAD} = 100mA		0.1	0.17	V	50.2__DROPOUT_100MA
	Tj = 25°C, I_{LOAD} = 500mA		0.19	0.27	V	50.3__DROPOUT_500MA
	Tj = 25°C, I_{LOAD} = 1A		0.24	0.3	V	50.4__DROPOUT_1000MA
I_{GND} GND pin current V_{IN} = $V_{OUT(NOMINAL)}$ + 1	Tj = 25°C, I_{LOAD} = 0mA		1	1.5	mA	55.1__GND_CURRENT_0mA
	Tj = 25°C, I_{LOAD} = 1mA		1.1	1.6	mA	55.2__GND_CURRENT_1mA
	Tj = 25°C, I_{LOAD} = 100mA		3.8	5.5	mA	55.3__GND_CURRENT_100mA
	Tj = 25°C, I_{LOAD} = 500mA		15	25	mA	55.4__GND_CURRENT_500mA
	Tj = 25°C, I_{LOAD} = 1A		35	80	mA	55.5__GND_CURRENT_1000m
I_{FB} FB pin bias current	Tj = 25°C		3	10	µA	15.5__I_FB_pin
I_{EN} EN pin current	Tj = 25°C, V_{EN} = 0V		0.01	1	µA	15.1__I_EN_0V
	Tj = 25°C, V_{EN} = 20V		3	30	µA	15.2__I_EN_20V
Quiescent current in shutdown	Tj = 25°C, V_{IN} = 6V, V_{EN} = 0V		0.01	1	µA	30.1__IQ_SHUTDOWN_VIN_6V
I_{REV} Input reverse leakage current	Tj = 25°C, V_{IN} = –20V, V_{OUT} = 0V			1	mA	5.1__IIL_VIN_-20V
I_{RO} Reverse output current	Tj = 25°C, V_{OUT} = 1.21V, V_{IN} < 1.21V		300	600	µA	4.1__IRO_VOUT_1.21_VIN_1.21V
						4.2__IRO_VOUT_1.21_VIN_0V

4 Total Ionizing Dose RHA Characterization Test Results

4.1 Total Ionizing Dose RHA Characterization Summary Results

The parametric data for the TPS73801-SEP is within data sheet limits up to 50krad(Si) for both biased and unbiased setup conditions.

Overall, the TPS73801-SEP showed a strong degree of hardness to LDR irradiation up to 50krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the data sheet electrical specification.

Measurements taken post-irradiation showed that the drift for samples that were biased was greater compared to the unbiased samples.

5 Applicable and Reference Documents

5.1 Applicable Documents

- TPS73801-SEP 1-A Low-Noise Fast-Transient-Response Low-Dropout Regulator in Space Enhanced Plastic data sheet
- TPS73801-SEP Single-Event Effects (SEE) Test Report

5.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MILSTD- 883 TM 1019. The document can be found at the DLA website.

6 Revision History

Changes from Revision B (April 2021) to Revision C (June 2024)	Page
• Updated from 30krad(Si) to 50krad	1
• Updated paragraph from 30krad(Si) to 50krad	5

A Specifications Requiring Clarification

Specifications Requiring Clarification

Table A-1. Specifications Requiring Clarification - Set #1

Data sheet specifications and input condition for which there is no parametric data and, therefore, not in the TID report. Functionality is assured by ATE testing.

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
V_{IN} Input voltage	Tj = 25°C	2.2	1.9	20	V
V_{EN} Shutdown threshold	V_{OUT} = OFF to ON		0.9	2	V
	V_{OUT} = ON to OFF	0.15	0.75		V

Table A-2. Specifications Requiring Clarification - Set #2

Data sheet specifications for which no data is available in TID report as specification was verified through bench testing. TID testing is by ATE.

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
V_N Output voltage noise	Tj = 25°C, C_{OUT} = 10µF, I_{LOAD} = 1A, BW = 10Hz to 100kHz		45		μV_{RMS}
PSRR Ripple rejection	Tj = 25°C, $V_{IN} – V_{OUT}$ = 1.5V (avg), V_{RIPPLE} = 0.5V_{P-P} f_{RIPPLE} = 120Hz, I_{LOAD} = 0.75A	55	63		dB
I_{CL} Current limit	Tj = 25°C, V_{IN} = 7V, V_{OUT} = 0V		2		A
	T_A = –55°C to 125°C, V_{IN} = $VOUT_{(NOMINAL)}$ + 1	1.6			A

B Total Ionizing Dose LDR Data Report

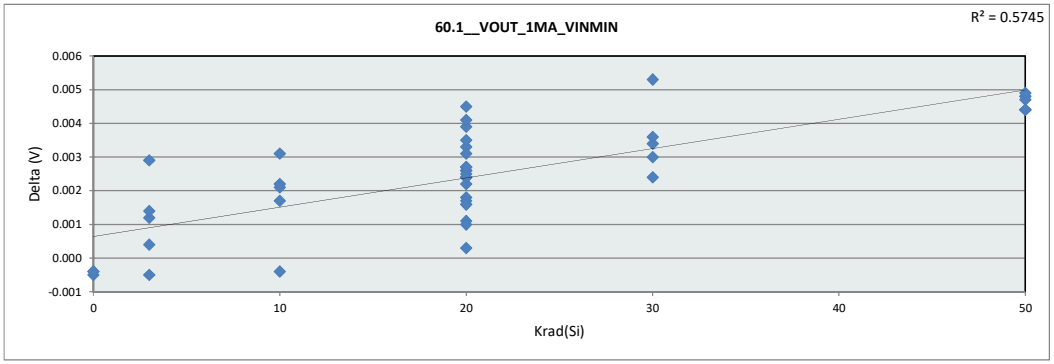
This appendix provides the TPS73801-SEP TID LDR data report. The report shows the variation for each parameter up to 50krad(Si).

TID LDR Data - BIASED
TPS73801-SEP

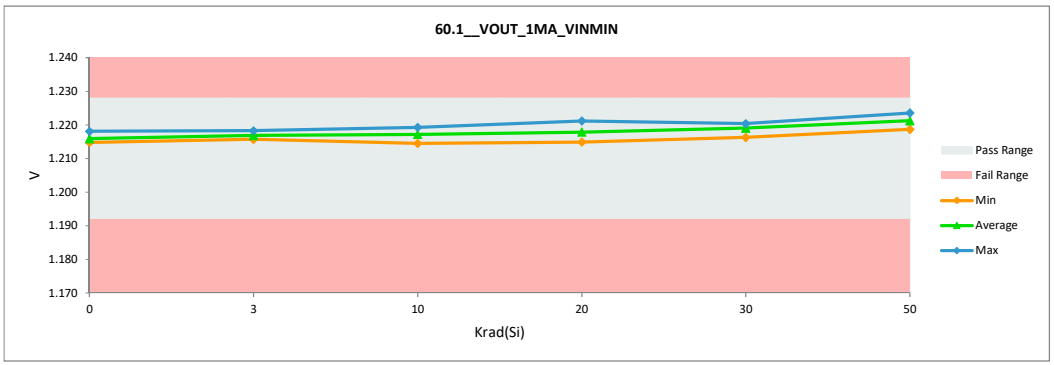
TID LDR Data (Biased)
TPS73801-SEP

	60.1__VOUT_1MA_VINMIN	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.228	1.228
Min Limit	1.192	1.192

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.215	1.215	0.000
0	69	1.219	1.218	0.000
0	70	1.215	1.215	0.000
3	1	1.215	1.218	0.003
3	2	1.214	1.216	0.001
3	3	1.216	1.216	-0.001
3	4	1.217	1.217	0.000
3	5	1.216	1.217	0.001
10	11	1.215	1.219	0.003
10	12	1.217	1.217	0.000
10	13	1.217	1.219	0.002
10	14	1.213	1.214	0.002
10	15	1.215	1.217	0.002
20	41	1.213	1.217	0.004
20	42	1.215	1.219	0.004
20	43	1.217	1.218	0.001
20	44	1.214	1.216	0.003
20	45	1.218	1.221	0.003
20	46	1.217	1.220	0.003
20	47	1.220	1.221	0.001
20	48	1.215	1.218	0.002
20	49	1.213	1.216	0.003
20	50	1.214	1.216	0.002
20	51	1.215	1.218	0.002
20	52	1.216	1.217	0.002
20	53	1.215	1.217	0.002
20	54	1.217	1.220	0.003
20	55	1.215	1.217	0.002
20	56	1.217	1.220	0.002
20	57	1.215	1.215	0.000
20	58	1.213	1.215	0.002
20	59	1.219	1.221	0.003
20	60	1.215	1.219	0.005
20	61	1.214	1.216	0.002
20	62	1.214	1.218	0.003
30	21	1.214	1.216	0.002
30	22	1.216	1.220	0.003
30	23	1.217	1.220	0.003
30	24	1.216	1.219	0.004
30	25	1.215	1.220	0.005
50	31	1.216	1.221	0.005
50	32	1.216	1.221	0.005
50	33	1.219	1.224	0.004
50	34	1.214	1.219	0.005
50	35	1.217	1.222	0.004
Max		1.220	1.224	0.005
Average		1.216	1.218	0.002
Min		1.213	1.214	-0.001
Std Dev		0.002	0.002	0.002



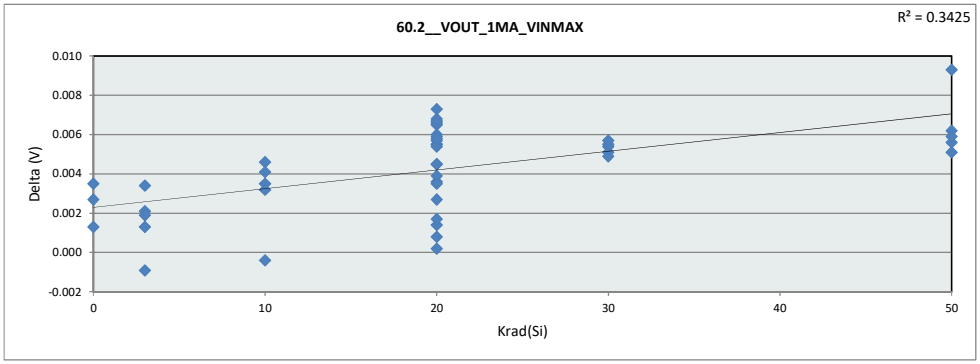
	60.1__VOUT_1MA_VINMIN					
Test Site						
Tester						
Test Number						
Max Limit	1.228	V				
Min Limit	1.192	V				
Krad(Si)	0	3	10	20	30	50
LL	1.192	1.192	1.192	1.192	1.192	1.192
Min	1.215	1.216	1.215	1.215	1.216	1.219
Average	1.216	1.217	1.217	1.218	1.219	1.221
Max	1.218	1.218	1.219	1.221	1.220	1.224
UL	1.228	1.228	1.228	1.228	1.228	1.228



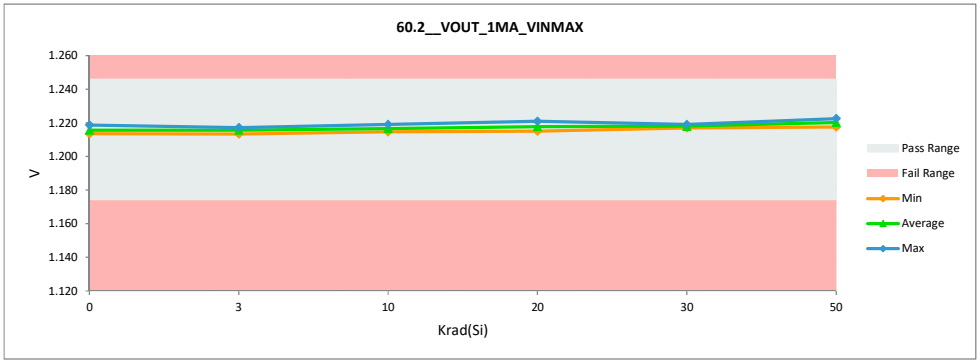
TID LDR Data (Biased)
TPS73801-SEP

	60.2__VOUT_1MA_VINMAX	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.212	1.214	0.001
0	69	1.216	1.219	0.003
0	70	1.211	1.215	0.003
3	1	1.214	1.217	0.003
3	2	1.211	1.213	0.002
3	3	1.217	1.216	-0.001
3	4	1.214	1.216	0.002
3	5	1.215	1.217	0.001
10	11	1.211	1.216	0.005
10	12	1.215	1.218	0.003
10	13	1.216	1.219	0.003
10	14	1.211	1.215	0.004
10	15	1.216	1.215	0.000
20	41	1.210	1.217	0.007
20	42	1.213	1.217	0.004
20	43	1.213	1.217	0.005
20	44	1.211	1.217	0.007
20	45	1.214	1.219	0.005
20	46	1.214	1.221	0.007
20	47	1.215	1.221	0.006
20	48	1.216	1.217	0.001
20	49	1.211	1.215	0.004
20	50	1.211	1.217	0.006
20	51	1.213	1.219	0.006
20	52	1.216	1.217	0.001
20	53	1.211	1.217	0.006
20	54	1.215	1.218	0.003
20	55	1.211	1.217	0.007
20	56	1.215	1.220	0.005
20	57	1.215	1.217	0.002
20	58	1.210	1.216	0.006
20	59	1.218	1.220	0.003
20	60	1.212	1.220	0.007
20	61	1.215	1.215	0.000
20	62	1.211	1.216	0.004
30	21	1.212	1.217	0.005
30	22	1.213	1.218	0.005
30	23	1.214	1.219	0.005
30	24	1.211	1.217	0.006
30	25	1.214	1.219	0.005
50	31	1.213	1.219	0.006
50	32	1.215	1.220	0.005
50	33	1.216	1.221	0.006
50	34	1.212	1.217	0.006
50	35	1.213	1.223	0.009
Max		1.218	1.223	0.009
Average		1.213	1.218	0.004
Min		1.210	1.213	-0.001
Std Dev		0.002	0.002	0.002



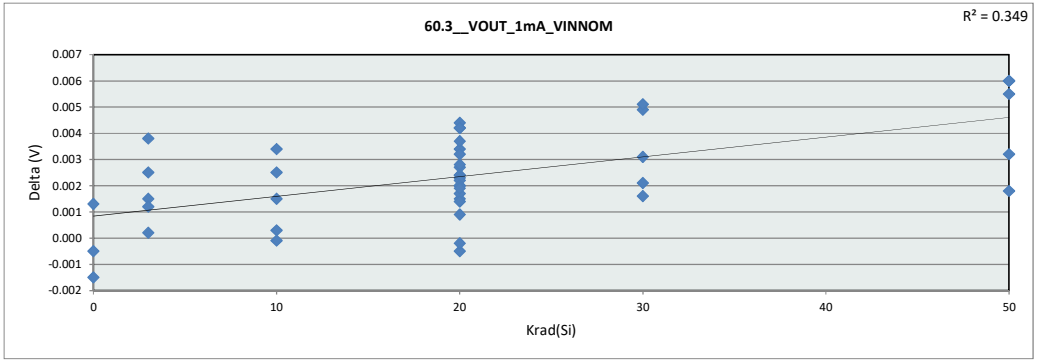
	60.2__VOUT_1MA_VINMAX					
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.214	1.213	1.215	1.215	1.217	1.218
Average	1.216	1.216	1.217	1.218	1.218	1.220
Max	1.219	1.217	1.219	1.221	1.219	1.223
UL	1.246	1.246	1.246	1.246	1.246	1.246



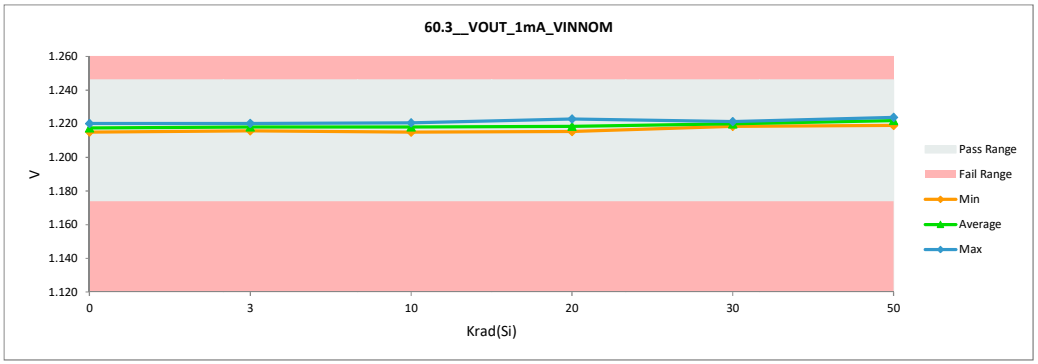
TID LDR Data (Biased)
TPS73801-SEP

	60.3__VOUT_1mA_VINNOM	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.217	1.215	-0.001
0	69	1.219	1.220	0.001
0	70	1.218	1.217	0.000
3	1	1.215	1.219	0.004
3	2	1.214	1.216	0.002
3	3	1.217	1.218	0.001
3	4	1.217	1.218	0.000
3	5	1.218	1.220	0.002
10	11	1.217	1.219	0.001
10	12	1.218	1.218	0.000
10	13	1.217	1.220	0.003
10	14	1.215	1.215	0.000
10	15	1.215	1.218	0.002
20	41	1.214	1.217	0.002
20	42	1.216	1.218	0.002
20	43	1.218	1.219	0.002
20	44	1.214	1.216	0.002
20	45	1.218	1.221	0.003
20	46	1.219	1.221	0.002
20	47	1.221	1.223	0.002
20	48	1.214	1.217	0.003
20	49	1.213	1.217	0.004
20	50	1.216	1.215	-0.001
20	51	1.216	1.219	0.003
20	52	1.215	1.219	0.004
20	53	1.218	1.217	0.000
20	54	1.217	1.220	0.004
20	55	1.215	1.217	0.002
20	56	1.218	1.220	0.002
20	57	1.215	1.217	0.001
20	58	1.215	1.217	0.002
20	59	1.219	1.222	0.003
20	60	1.217	1.221	0.004
20	61	1.214	1.216	0.002
20	62	1.216	1.217	0.001
30	21	1.216	1.218	0.002
30	22	1.216	1.221	0.005
30	23	1.217	1.219	0.002
30	24	1.216	1.221	0.005
30	25	1.217	1.220	0.003
50	31	1.216	1.222	0.006
50	32	1.216	1.222	0.006
50	33	1.220	1.222	0.002
50	34	1.216	1.219	0.003
50	35	1.218	1.224	0.005
Max		1.221	1.224	0.006
Average		1.217	1.219	0.002
Min		1.213	1.215	-0.001
Std Dev		0.002	0.002	0.002



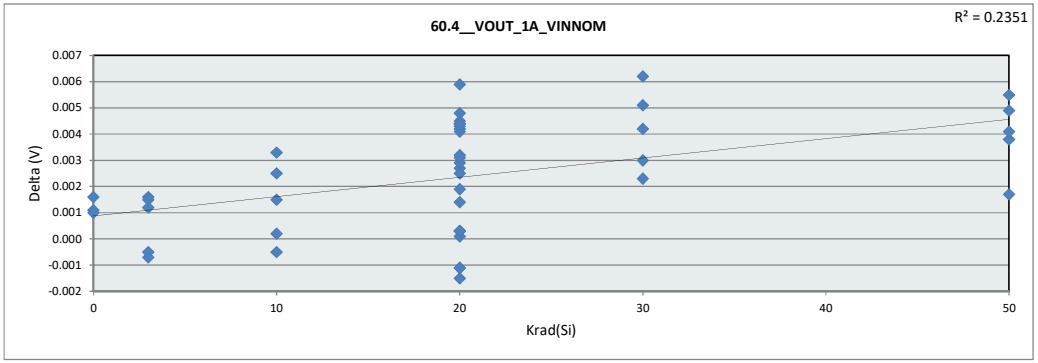
	60.3__VOUT_1mA_VINNOM					
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.216	1.215	1.215	1.218	1.219
Average	1.218	1.218	1.218	1.218	1.220	1.222
Max	1.220	1.220	1.221	1.223	1.221	1.224
UL	1.246	1.246	1.246	1.246	1.246	1.246



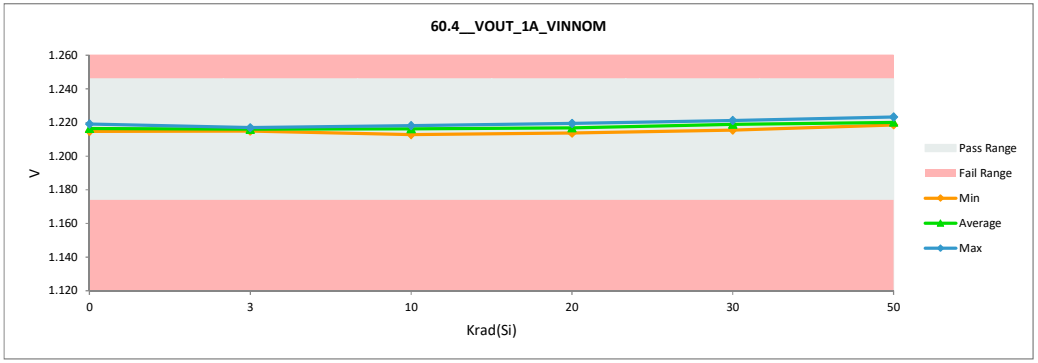
TID LDR Data (Biased)
TPS73801-SEP

	60.4__VOUT_1A_VINNOM	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.214	1.215	0.002
0	69	1.218	1.219	0.001
0	70	1.214	1.215	0.001
3	1	1.215	1.216	0.002
3	2	1.214	1.215	0.001
3	3	1.215	1.217	0.002
3	4	1.216	1.216	0.000
3	5	1.217	1.216	-0.001
10	11	1.215	1.218	0.002
10	12	1.216	1.216	0.000
10	13	1.217	1.218	0.002
10	14	1.213	1.213	0.000
10	15	1.214	1.217	0.003
20	41	1.212	1.217	0.005
20	42	1.214	1.218	0.005
20	43	1.214	1.217	0.003
20	44	1.211	1.217	0.006
20	45	1.214	1.219	0.004
20	46	1.215	1.219	0.004
20	47	1.219	1.219	0.000
20	48	1.216	1.216	0.000
20	49	1.214	1.217	0.003
20	50	1.215	1.215	0.000
20	51	1.217	1.217	0.000
20	52	1.216	1.217	0.001
20	53	1.213	1.217	0.004
20	54	1.218	1.217	-0.001
20	55	1.212	1.217	0.004
20	56	1.215	1.218	0.003
20	57	1.213	1.215	0.002
20	58	1.215	1.214	-0.001
20	59	1.216	1.218	0.002
20	60	1.213	1.217	0.004
20	61	1.211	1.214	0.003
20	62	1.215	1.214	-0.001
30	21	1.213	1.215	0.002
30	22	1.215	1.219	0.004
30	23	1.216	1.221	0.005
30	24	1.216	1.219	0.003
30	25	1.215	1.221	0.006
50	31	1.215	1.219	0.004
50	32	1.217	1.219	0.002
50	33	1.218	1.223	0.005
50	34	1.215	1.220	0.004
50	35	1.216	1.220	0.005
	Max	1.219	1.223	0.006
	Average	1.215	1.217	0.002
	Min	1.211	1.213	-0.001
	Std Dev	0.002	0.002	0.002



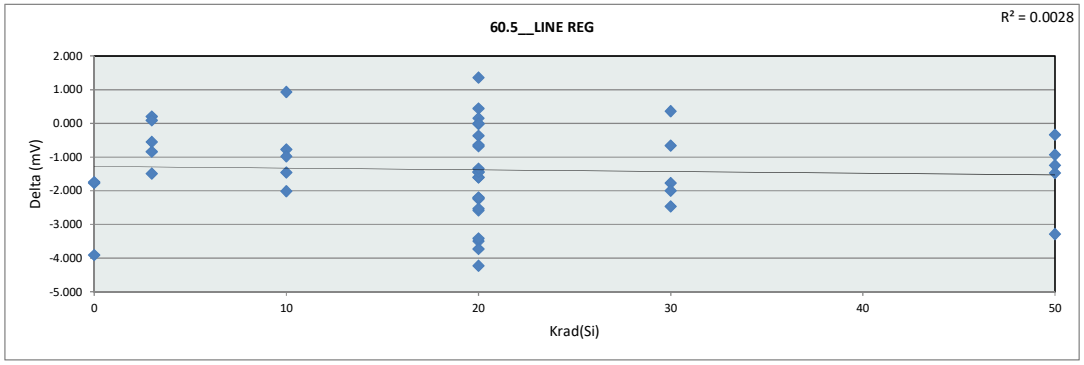
	60.4__VOUT_1A_VINNOM					
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.215	1.213	1.214	1.216	1.219
Average	1.216	1.216	1.216	1.217	1.219	1.220
Max	1.219	1.217	1.218	1.219	1.221	1.223
UL	1.246	1.246	1.246	1.246	1.246	1.246



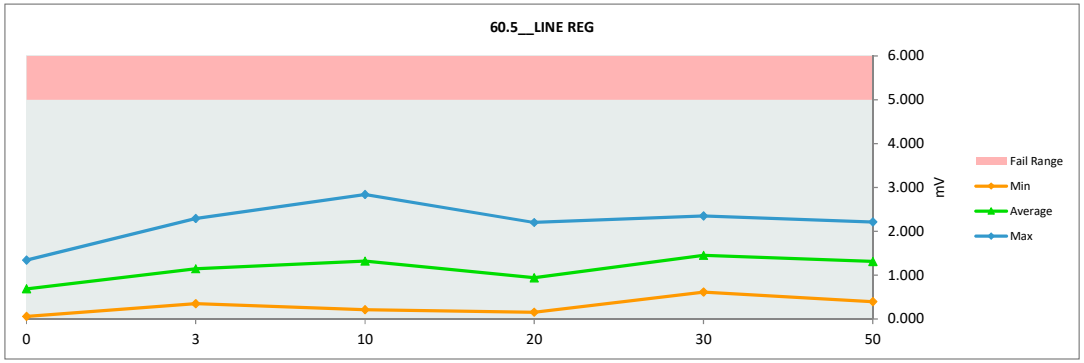
TID LDR Data (Biased)
TPS73801-SEP

	60.5__LINE REG	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	5	5
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	3.112	1.342	-1.771
0	69	2.410	0.666	-1.744
0	70	3.971	0.060	-3.912
3	1	1.480	0.928	-0.552
3	2	3.136	2.293	-0.843
3	3	0.151	0.349	0.198
3	4	2.809	1.314	-1.495
3	5	0.758	0.842	0.084
10	11	4.301	2.840	-1.461
10	12	2.370	1.597	-0.773
10	13	1.196	0.213	-0.982
10	14	2.256	0.239	-2.017
10	15	0.776	1.707	0.931
20	41	2.776	0.191	-2.586
20	42	1.535	1.973	0.439
20	43	4.156	0.655	-3.501
20	44	2.761	1.160	-1.601
20	45	3.692	1.450	-2.242
20	46	3.381	0.843	-2.538
20	47	4.384	0.157	-4.227
20	48	0.563	0.541	-0.022
20	49	1.333	0.961	-0.373
20	50	3.278	1.057	-2.221
20	51	2.367	0.912	-1.455
20	52	0.474	0.621	0.147
20	53	4.301	0.885	-3.416
20	54	2.247	1.564	-0.682
20	55	4.088	0.356	-3.732
20	56	2.339	0.734	-1.605
20	57	0.846	2.202	1.355
20	58	2.779	1.337	-1.442
20	59	0.719	0.713	-0.006
20	60	2.504	0.304	-2.200
20	61	1.007	0.366	-0.641
20	62	3.051	1.708	-1.343
30	21	1.888	1.224	-0.663
30	22	3.347	1.573	-1.774
30	23	3.084	0.614	-2.470
30	24	4.348	2.348	-2.000
30	25	1.132	1.494	0.362
50	31	3.422	1.944	-1.478
50	32	0.739	0.395	-0.344
50	33	3.458	2.213	-1.245
50	34	2.168	1.232	-0.936
50	35	4.054	0.765	-3.288
Max		4.384	2.840	1.355
Average		2.466	1.086	-1.379
Min		0.151	0.060	-4.227
Std Dev		1.247	0.687	1.306



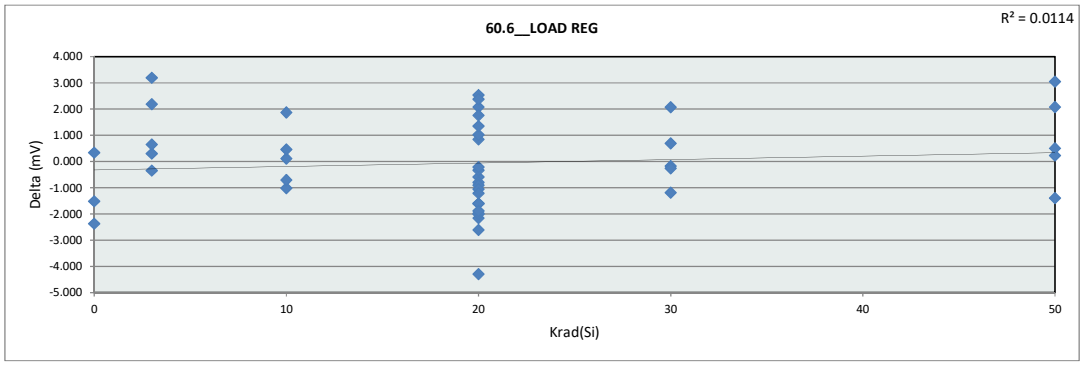
	60.5__LINE REG					
Test Site						
Tester						
Test Number						
Max Limit	5	mV				
Min Limit		mV				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.060	0.349	0.213	0.157	0.614	0.395
Average	0.689	1.145	1.319	0.940	1.451	1.310
Max	1.342	2.293	2.840	2.202	2.348	2.213
UL	5.000	5.000	5.000	5.000	5.000	5.000



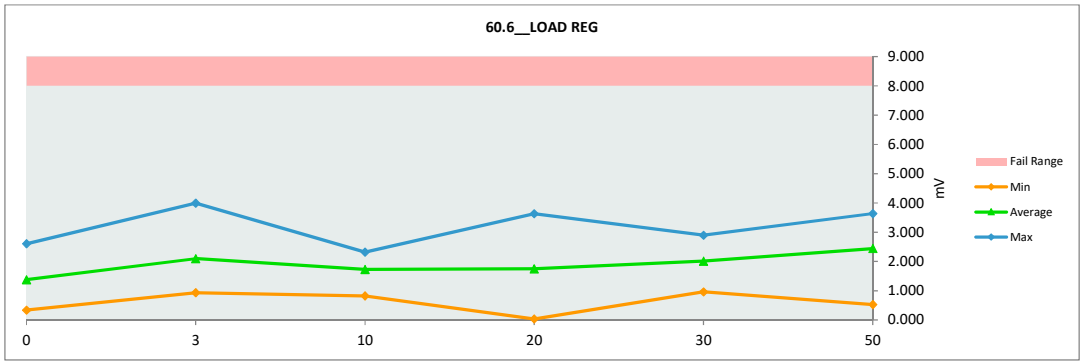
TID LDR Data (Biased)
TPS73801-SEP

	60.6__LOAD REG	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	8	8
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	2.708	0.338	-2.370
0	69	0.831	1.174	0.343
0	70	4.126	2.607	-1.518
3	1	0.404	2.589	2.185
3	2	0.630	0.935	0.305
3	3	1.391	1.042	-0.349
3	4	1.279	1.925	0.646
3	5	0.792	3.989	3.197
10	11	2.188	1.176	-1.012
10	12	1.993	2.108	0.115
10	13	0.448	2.321	1.873
10	14	1.766	2.223	0.457
10	15	1.525	0.820	-0.705
20	41	2.263	0.104	-2.158
20	42	2.043	0.033	-2.011
20	43	3.869	2.265	-1.604
20	44	2.921	0.940	-1.981
20	45	3.856	2.256	-1.600
20	46	3.681	1.792	-1.889
20	47	1.269	3.344	2.075
20	48	1.813	1.223	-0.590
20	49	0.951	0.617	-0.335
20	50	1.066	0.268	-0.798
20	51	0.792	1.641	0.849
20	52	1.004	2.025	1.021
20	53	4.688	0.389	-4.299
20	54	1.531	3.292	1.761
20	55	2.762	0.147	-2.615
20	56	2.305	1.400	-0.905
20	57	2.167	1.116	-1.052
20	58	0.290	2.825	2.535
20	59	2.281	3.629	1.348
20	60	3.827	3.616	-0.211
20	61	3.310	2.095	-1.215
20	62	1.056	3.434	2.378
30	21	3.067	2.896	-0.171
30	22	1.237	1.930	0.693
30	23	1.948	1.691	-0.257
30	24	0.520	2.586	2.066
30	25	2.150	0.959	-1.191
50	31	1.529	3.609	2.079
50	32	0.589	3.638	3.049
50	33	2.546	1.154	-1.392
50	34	0.293	0.526	0.233
50	35	2.776	3.277	0.502
Max		4.688	3.989	3.197
Average		1.922	1.866	-0.056
Min		0.290	0.033	-4.299
Std Dev		1.152	1.136	1.687



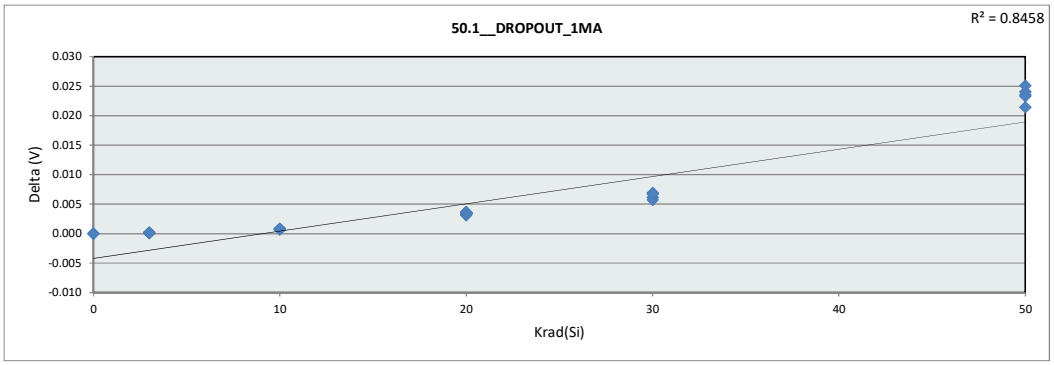
	60.6__LOAD REG					
Test Site						
Tester						
Test Number						
Max Limit	8	mV				
Min Limit		mV				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.338	0.935	0.820	0.033	0.959	0.526
Average	1.373	2.096	1.730	1.748	2.012	2.441
Max	2.607	3.989	2.321	3.629	2.896	3.638
UL	8.000	8.000	8.000	8.000	8.000	8.000



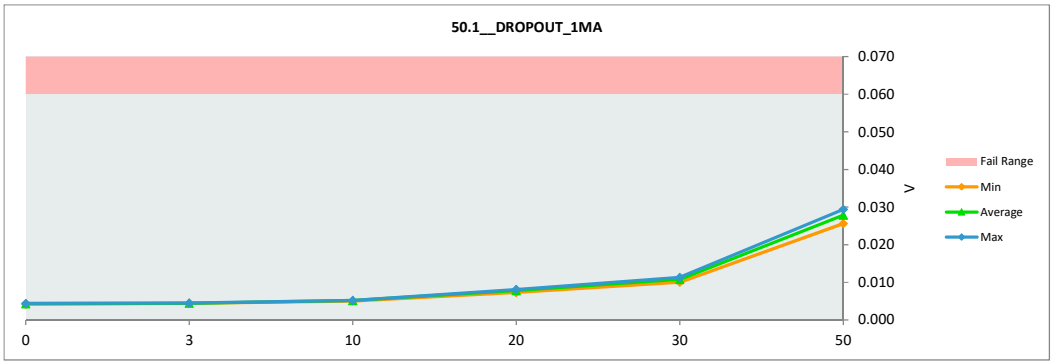
TID LDR Data (Biased)
TPS73801-SEP

	50.1__DROPOUT_1MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.06	0.06
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.004	0.004	0.000
0	69	0.004	0.004	0.000
0	70	0.004	0.004	0.000
3	1	0.004	0.004	0.000
3	2	0.004	0.004	0.000
3	3	0.004	0.004	0.000
3	4	0.004	0.004	0.000
3	5	0.004	0.004	0.000
10	11	0.004	0.005	0.001
10	12	0.004	0.005	0.001
10	13	0.004	0.005	0.001
10	14	0.004	0.005	0.001
10	15	0.004	0.005	0.001
20	41	0.004	0.007	0.003
20	42	0.004	0.008	0.003
20	43	0.004	0.008	0.003
20	44	0.004	0.008	0.003
20	45	0.004	0.008	0.004
20	46	0.004	0.008	0.003
20	47	0.004	0.008	0.003
20	48	0.004	0.008	0.003
20	49	0.004	0.007	0.003
20	50	0.004	0.008	0.003
20	51	0.004	0.007	0.003
20	52	0.004	0.008	0.003
20	53	0.004	0.008	0.003
20	54	0.004	0.008	0.003
20	55	0.004	0.008	0.004
20	56	0.004	0.008	0.003
20	57	0.004	0.008	0.004
20	58	0.004	0.008	0.004
20	59	0.004	0.008	0.004
20	60	0.005	0.008	0.004
20	61	0.004	0.008	0.003
20	62	0.004	0.008	0.003
30	21	0.004	0.010	0.006
30	22	0.004	0.011	0.007
30	23	0.004	0.010	0.006
30	24	0.004	0.011	0.007
30	25	0.004	0.011	0.007
50	31	0.005	0.029	0.024
50	32	0.004	0.028	0.023
50	33	0.004	0.026	0.021
50	34	0.004	0.028	0.023
50	35	0.004	0.029	0.025
Max		0.005	0.029	0.025
Average		0.004	0.009	0.005
Min		0.004	0.004	0.000
Std Dev		0.000	0.007	0.007



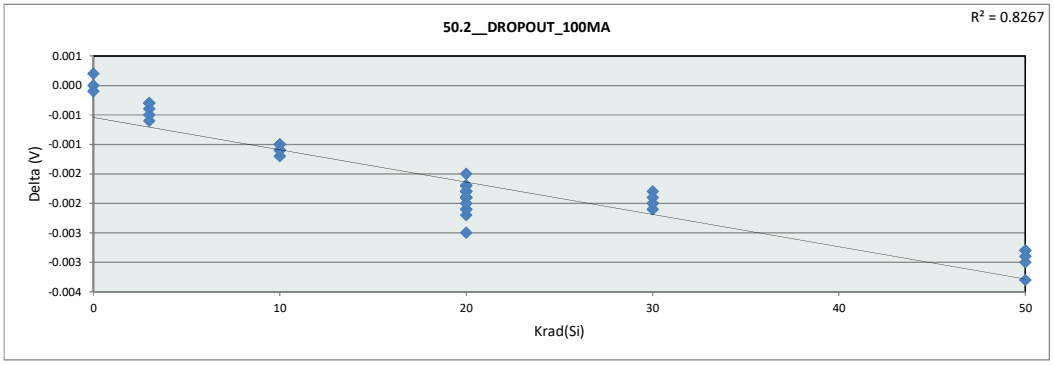
	50.1__DROPOUT_1MA					
Test Site						
Tester						
Test Number						
Max Limit	0.06	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.004	0.004	0.005	0.007	0.010	0.026
Average	0.004	0.004	0.005	0.008	0.011	0.028
Max	0.004	0.005	0.005	0.008	0.011	0.029
UL	0.060	0.060	0.060	0.060	0.060	0.060



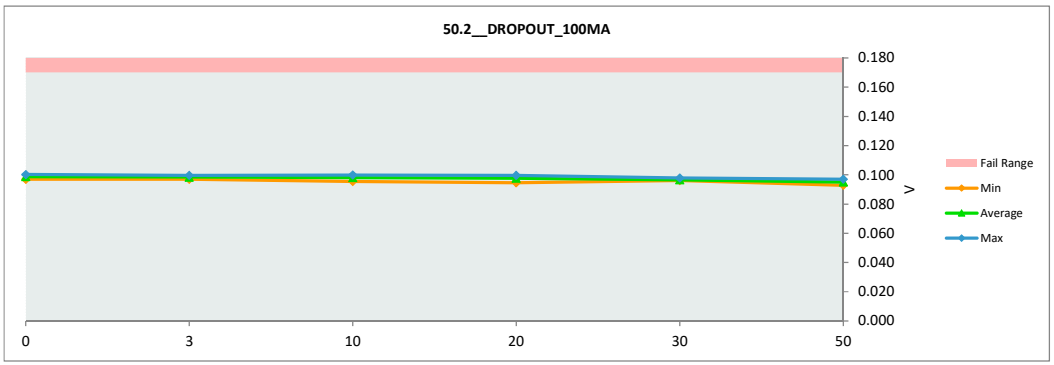
TID LDR Data (Biased)
TPS73801-SEP

	50.2__DROPOUT_100MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.17	0.17
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.100	0.100	0.000
0	69	0.097	0.097	0.000
0	70	0.099	0.099	0.000
3	1	0.098	0.098	0.000
3	2	0.100	0.100	0.000
3	3	0.100	0.100	-0.001
3	4	0.099	0.098	0.000
3	5	0.097	0.097	-0.001
10	11	0.099	0.098	-0.001
10	12	0.098	0.097	-0.001
10	13	0.097	0.095	-0.001
10	14	0.101	0.100	-0.001
10	15	0.101	0.100	-0.001
20	41	0.101	0.099	-0.002
20	42	0.098	0.097	-0.002
20	43	0.100	0.098	-0.002
20	44	0.101	0.099	-0.002
20	45	0.097	0.095	-0.002
20	46	0.098	0.096	-0.002
20	47	0.096	0.095	-0.002
20	48	0.100	0.097	-0.002
20	49	0.101	0.098	-0.003
20	50	0.101	0.099	-0.002
20	51	0.099	0.097	-0.002
20	52	0.099	0.097	-0.002
20	53	0.100	0.098	-0.002
20	54	0.099	0.097	-0.002
20	55	0.100	0.098	-0.002
20	56	0.099	0.097	-0.001
20	57	0.101	0.099	-0.002
20	58	0.102	0.100	-0.002
20	59	0.097	0.095	-0.002
20	60	0.100	0.098	-0.002
20	61	0.101	0.100	-0.002
20	62	0.100	0.098	-0.002
30	21	0.100	0.098	-0.002
30	22	0.098	0.096	-0.002
30	23	0.098	0.096	-0.002
30	24	0.098	0.097	-0.002
30	25	0.098	0.096	-0.002
50	31	0.099	0.096	-0.003
50	32	0.098	0.095	-0.003
50	33	0.096	0.093	-0.003
50	34	0.100	0.097	-0.003
50	35	0.097	0.094	-0.003
Max		0.102	0.100	0.000
Average		0.099	0.097	-0.002
Min		0.096	0.093	-0.003
Std Dev		0.001	0.002	0.001



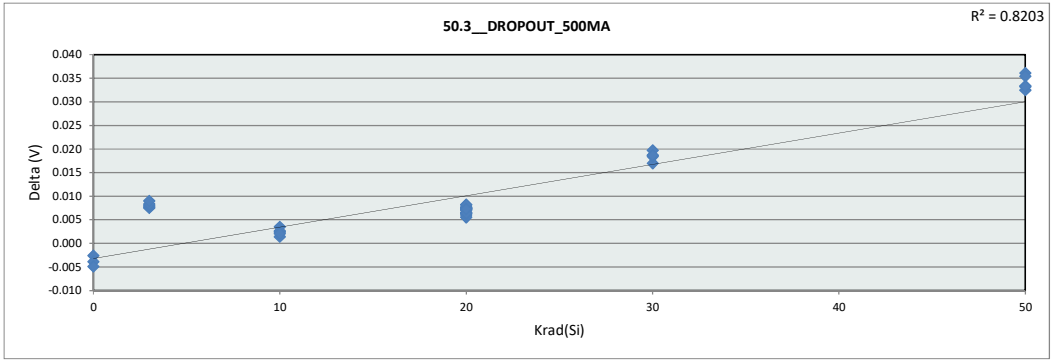
	50.2__DROPOUT_100MA					
Test Site						
Tester						
Test Number						
Max Limit	0.17	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.097	0.097	0.095	0.095	0.096	0.093
Average	0.099	0.098	0.098	0.098	0.097	0.095
Max	0.100	0.100	0.100	0.100	0.098	0.097
UL	0.170	0.170	0.170	0.170	0.170	0.170



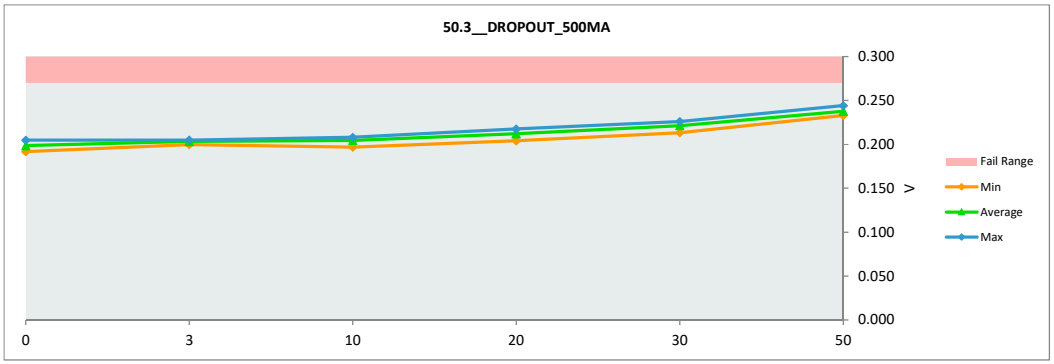
TID LDR Data (Biased)
TPS73801-SEP

	50.3__DROPOUT_500MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.27	0.27
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.207	0.205	-0.003
0	69	0.196	0.192	-0.004
0	70	0.205	0.200	-0.005
3	1	0.196	0.203	0.007
3	2	0.196	0.203	0.008
3	3	0.192	0.200	0.008
3	4	0.196	0.204	0.008
3	5	0.196	0.205	0.009
10	11	0.203	0.207	0.003
10	12	0.201	0.203	0.002
10	13	0.194	0.197	0.003
10	14	0.207	0.208	0.001
10	15	0.206	0.208	0.002
20	41	0.200	0.207	0.007
20	42	0.206	0.212	0.006
20	43	0.209	0.217	0.008
20	44	0.203	0.209	0.007
20	45	0.204	0.211	0.007
20	46	0.206	0.212	0.006
20	47	0.204	0.211	0.006
20	48	0.206	0.214	0.007
20	49	0.200	0.207	0.007
20	50	0.208	0.213	0.005
20	51	0.197	0.204	0.007
20	52	0.210	0.215	0.006
20	53	0.202	0.210	0.007
20	54	0.201	0.208	0.008
20	55	0.209	0.218	0.008
20	56	0.205	0.213	0.007
20	57	0.206	0.213	0.008
20	58	0.208	0.216	0.008
20	59	0.206	0.213	0.007
20	60	0.210	0.216	0.006
20	61	0.208	0.214	0.006
20	62	0.203	0.211	0.007
30	21	0.205	0.223	0.019
30	22	0.206	0.226	0.020
30	23	0.196	0.213	0.017
30	24	0.204	0.222	0.018
30	25	0.204	0.223	0.019
50	31	0.208	0.244	0.036
50	32	0.198	0.233	0.035
50	33	0.200	0.233	0.032
50	34	0.203	0.236	0.033
50	35	0.209	0.242	0.033
Max		0.210	0.244	0.036
Average		0.203	0.213	0.010
Min		0.192	0.192	-0.005
Std Dev		0.005	0.011	0.010



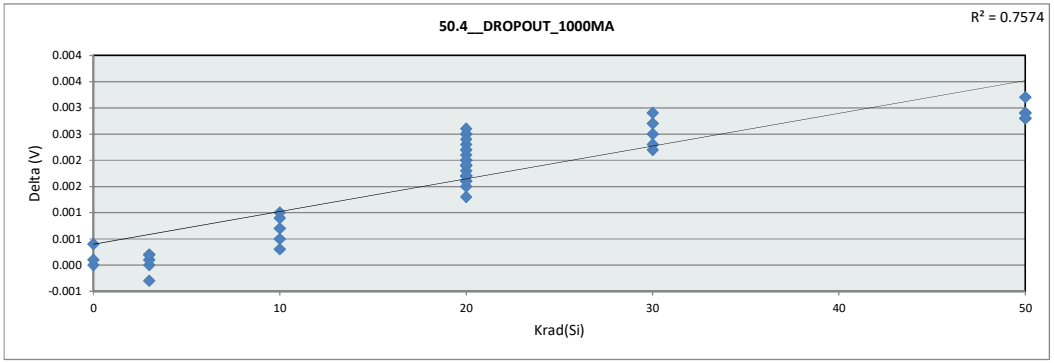
	50.3__DROPOUT_500MA					
Test Site						
Tester						
Test Number						
Max Limit	0.27	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.192	0.200	0.197	0.204	0.213	0.233
Average	0.199	0.203	0.204	0.212	0.221	0.238
Max	0.205	0.205	0.208	0.218	0.226	0.244
UL	0.270	0.270	0.270	0.270	0.270	0.270



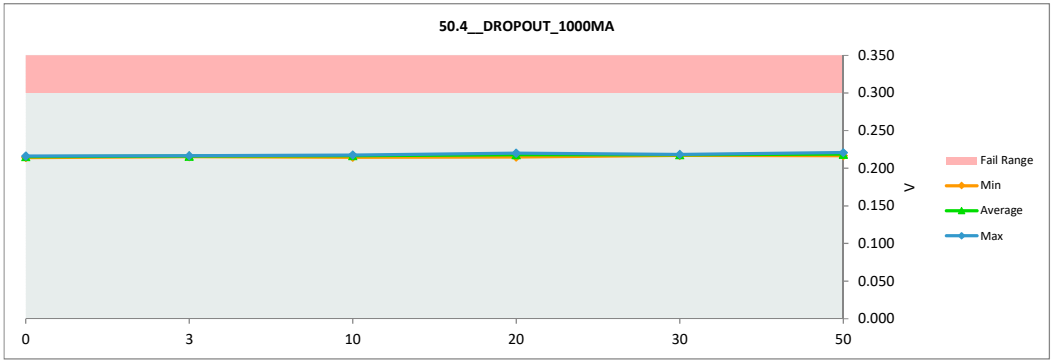
TID LDR Data (Biased)
TPS73801-SEP

	50.4__DROPOUT_1000MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.3	0.3
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.216	0.216	0.000
0	69	0.214	0.214	0.000
0	70	0.216	0.216	0.000
3	1	0.215	0.215	0.000
3	2	0.216	0.217	0.000
3	3	0.216	0.217	0.000
3	4	0.216	0.216	0.000
3	5	0.216	0.216	0.000
10	11	0.216	0.217	0.000
10	12	0.216	0.217	0.001
10	13	0.214	0.214	0.000
10	14	0.217	0.218	0.001
10	15	0.217	0.218	0.001
20	41	0.215	0.217	0.002
20	42	0.215	0.217	0.002
20	43	0.217	0.219	0.002
20	44	0.216	0.218	0.002
20	45	0.214	0.216	0.002
20	46	0.216	0.218	0.002
20	47	0.215	0.218	0.002
20	48	0.216	0.218	0.002
20	49	0.214	0.215	0.001
20	50	0.217	0.218	0.001
20	51	0.215	0.216	0.002
20	52	0.215	0.218	0.002
20	53	0.216	0.218	0.002
20	54	0.216	0.218	0.002
20	55	0.216	0.219	0.002
20	56	0.217	0.219	0.003
20	57	0.216	0.218	0.002
20	58	0.217	0.219	0.002
20	59	0.215	0.217	0.002
20	60	0.218	0.220	0.002
20	61	0.217	0.219	0.002
20	62	0.215	0.217	0.002
30	21	0.216	0.218	0.002
30	22	0.216	0.218	0.002
30	23	0.215	0.217	0.002
30	24	0.215	0.218	0.003
30	25	0.216	0.218	0.003
50	31	0.218	0.221	0.003
50	32	0.216	0.219	0.003
50	33	0.214	0.217	0.003
50	34	0.216	0.219	0.003
50	35	0.215	0.219	0.003
Max		0.218	0.221	0.003
Average		0.216	0.217	0.002
Min		0.214	0.214	0.000
Std Dev		0.001	0.001	0.001



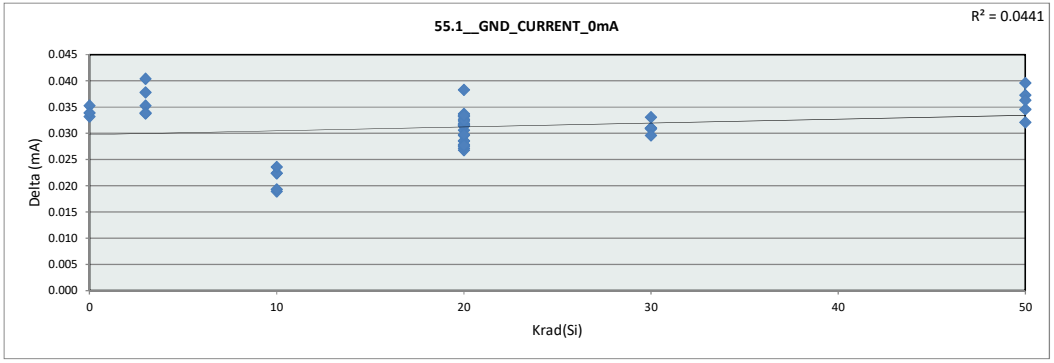
	50.4__DROPOUT_1000MA					
Test Site						
Tester						
Test Number						
Max Limit	0.3	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.214	0.215	0.215	0.215	0.217	0.217
Average	0.215	0.216	0.217	0.218	0.218	0.219
Max	0.216	0.217	0.218	0.220	0.218	0.221
UL	0.300	0.300	0.300	0.300	0.300	0.300



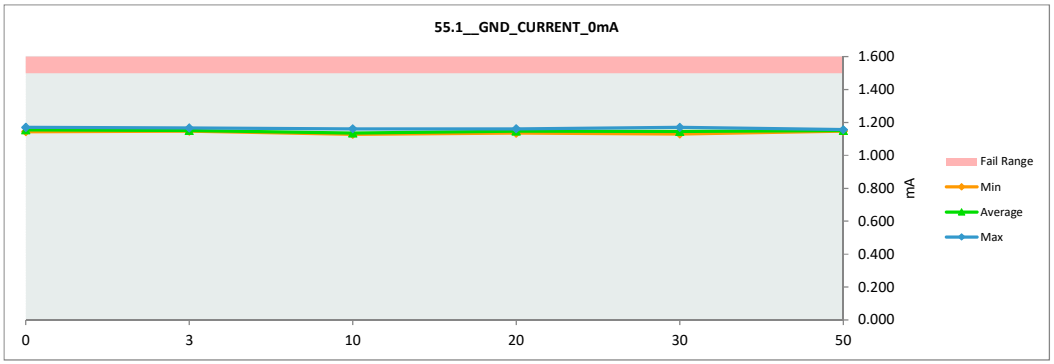
TID LDR Data (Biased)
TPS73801-SEP

	55.1__GND_CURRENT_0mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	1.5	1.5
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.110	1.144	0.033
0	69	1.135	1.170	0.035
0	70	1.118	1.152	0.034
3	1	1.110	1.146	0.035
3	2	1.115	1.149	0.034
3	3	1.126	1.166	0.040
3	4	1.110	1.147	0.038
3	5	1.112	1.146	0.034
10	11	1.111	1.130	0.019
10	12	1.112	1.132	0.019
10	13	1.139	1.161	0.022
10	14	1.105	1.128	0.022
10	15	1.107	1.131	0.024
20	41	1.129	1.161	0.032
20	42	1.113	1.151	0.038
20	43	1.114	1.148	0.034
20	44	1.111	1.144	0.033
20	45	1.113	1.145	0.032
20	46	1.123	1.151	0.028
20	47	1.119	1.151	0.032
20	48	1.107	1.140	0.033
20	49	1.131	1.160	0.029
20	50	1.107	1.134	0.027
20	51	1.130	1.160	0.030
20	52	1.112	1.142	0.031
20	53	1.115	1.147	0.032
20	54	1.109	1.140	0.031
20	55	1.112	1.145	0.033
20	56	1.123	1.155	0.032
20	57	1.113	1.147	0.033
20	58	1.117	1.144	0.027
20	59	1.113	1.141	0.028
20	60	1.112	1.140	0.028
20	61	1.110	1.140	0.030
20	62	1.118	1.146	0.028
30	21	1.111	1.142	0.031
30	22	1.109	1.142	0.033
30	23	1.139	1.170	0.031
30	24	1.110	1.141	0.031
30	25	1.100	1.130	0.030
50	31	1.115	1.154	0.040
50	32	1.114	1.148	0.035
50	33	1.112	1.149	0.037
50	34	1.115	1.148	0.032
50	35	1.120	1.156	0.036
Max		1.139	1.170	0.040
Average		1.116	1.147	0.031
Min		1.100	1.128	0.019
Std Dev		0.009	0.010	0.005



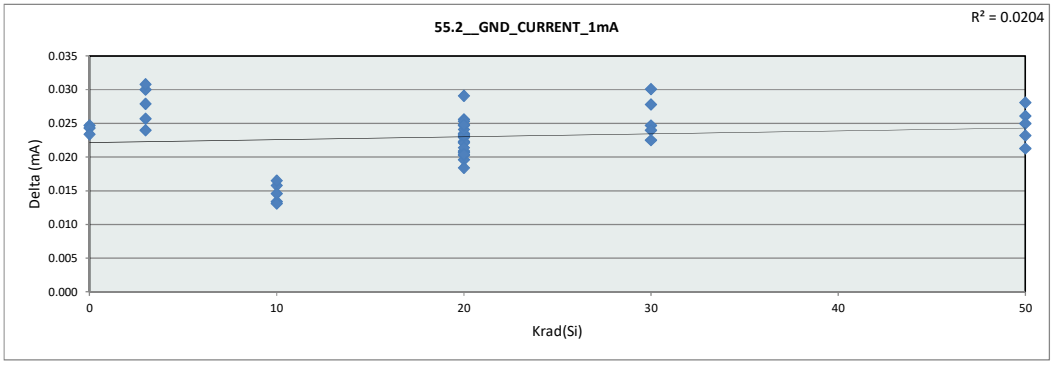
	55.1__GND_CURRENT_0mA					
Test Site						
Tester						
Test Number						
Max Limit	1.5	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.144	1.146	1.128	1.134	1.130	1.148
Average	1.155	1.151	1.136	1.147	1.145	1.151
Max	1.170	1.166	1.161	1.161	1.170	1.156
UL	1.500	1.500	1.500	1.500	1.500	1.500



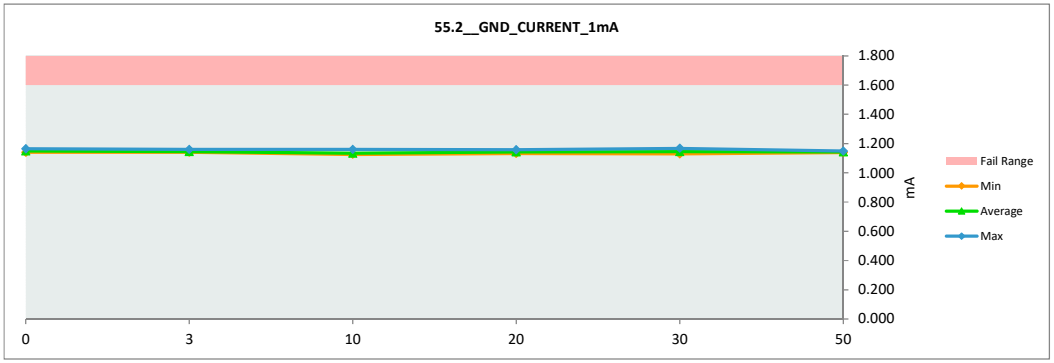
TID LDR Data (Biased)
TPS73801-SEP

	55.2__GND_CURRENT_1mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	1.6	1.6
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.115	1.140	0.025
0	69	1.140	1.164	0.024
0	70	1.123	1.146	0.023
3	1	1.113	1.141	0.028
3	2	1.119	1.143	0.024
3	3	1.130	1.160	0.030
3	4	1.112	1.143	0.031
3	5	1.117	1.142	0.026
10	11	1.115	1.129	0.013
10	12	1.116	1.129	0.013
10	13	1.145	1.160	0.016
10	14	1.111	1.125	0.015
10	15	1.112	1.129	0.016
20	41	1.135	1.158	0.023
20	42	1.117	1.146	0.029
20	43	1.121	1.144	0.022
20	44	1.115	1.139	0.024
20	45	1.118	1.141	0.023
20	46	1.128	1.148	0.020
20	47	1.124	1.146	0.022
20	48	1.112	1.135	0.023
20	49	1.136	1.158	0.022
20	50	1.111	1.132	0.021
20	51	1.135	1.156	0.021
20	52	1.116	1.139	0.023
20	53	1.117	1.143	0.026
20	54	1.114	1.139	0.025
20	55	1.117	1.141	0.024
20	56	1.127	1.152	0.025
20	57	1.119	1.144	0.025
20	58	1.122	1.140	0.018
20	59	1.118	1.139	0.021
20	60	1.117	1.139	0.021
20	61	1.116	1.136	0.020
20	62	1.122	1.142	0.020
30	21	1.115	1.143	0.028
30	22	1.113	1.143	0.030
30	23	1.145	1.168	0.023
30	24	1.115	1.139	0.025
30	25	1.104	1.128	0.024
50	31	1.120	1.148	0.028
50	32	1.117	1.140	0.023
50	33	1.116	1.142	0.026
50	34	1.118	1.140	0.021
50	35	1.124	1.149	0.025
	Max	1.145	1.168	0.031
	Average	1.120	1.143	0.023
	Min	1.104	1.125	0.013
	Std Dev	0.009	0.009	0.004



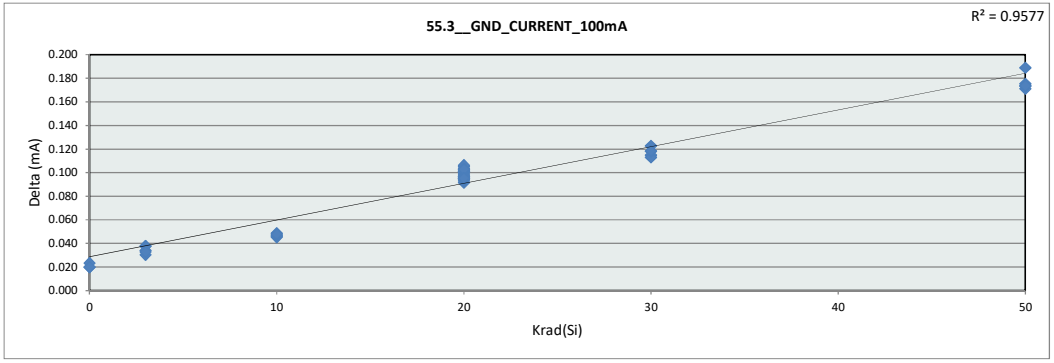
	55.2__GND_CURRENT_1mA					
Test Site						
Tester						
Test Number						
Max Limit	1.6	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.140	1.141	1.125	1.132	1.128	1.140
Average	1.150	1.146	1.134	1.143	1.144	1.144
Max	1.164	1.160	1.160	1.158	1.168	1.149
UL	1.600	1.600	1.600	1.600	1.600	1.600



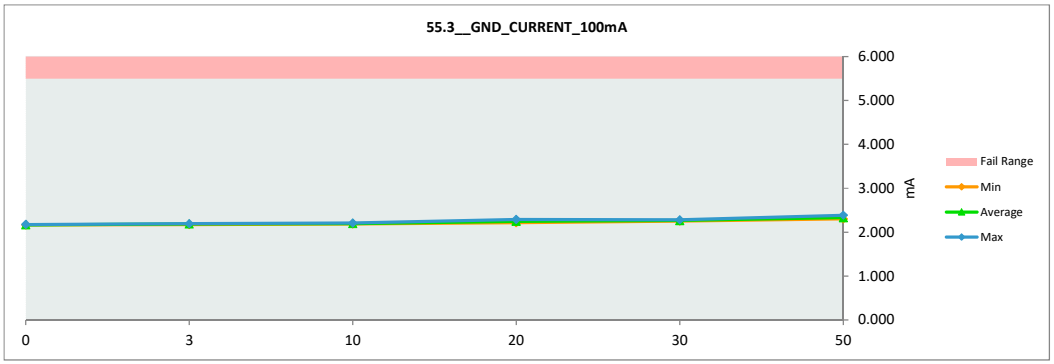
TID LDR Data (Biased)
TPS73801-SEP

	55.3__GND_CURRENT_100mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	5.5	5.5
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	2.146	2.165	0.020
0	69	2.141	2.165	0.023
0	70	2.156	2.176	0.020
3	1	2.141	2.175	0.034
3	2	2.153	2.183	0.030
3	3	2.150	2.188	0.038
3	4	2.149	2.187	0.037
3	5	2.163	2.196	0.033
10	11	2.151	2.197	0.045
10	12	2.141	2.187	0.046
10	13	2.160	2.209	0.049
10	14	2.144	2.190	0.047
10	15	2.145	2.193	0.048
20	41	2.135	2.232	0.097
20	42	2.142	2.246	0.104
20	43	2.164	2.260	0.096
20	44	2.132	2.231	0.099
20	45	2.135	2.231	0.096
20	46	2.167	2.263	0.097
20	47	2.167	2.267	0.100
20	48	2.148	2.248	0.101
20	49	2.124	2.219	0.095
20	50	2.141	2.233	0.091
20	51	2.137	2.230	0.093
20	52	2.145	2.245	0.101
20	53	2.145	2.246	0.101
20	54	2.128	2.230	0.102
20	55	2.160	2.266	0.105
20	56	2.187	2.293	0.106
20	57	2.148	2.251	0.103
20	58	2.161	2.255	0.094
20	59	2.144	2.239	0.095
20	60	2.189	2.291	0.103
20	61	2.149	2.244	0.095
20	62	2.145	2.240	0.095
30	21	2.148	2.262	0.115
30	22	2.158	2.281	0.123
30	23	2.155	2.268	0.113
30	24	2.145	2.263	0.118
30	25	2.133	2.251	0.118
50	31	2.198	2.386	0.189
50	32	2.136	2.311	0.175
50	33	2.129	2.300	0.171
50	34	2.145	2.318	0.173
50	35	2.163	2.337	0.173
	Max	2.198	2.386	0.189
	Average	2.150	2.241	0.091
	Min	2.124	2.165	0.020
	Std Dev	0.015	0.047	0.043



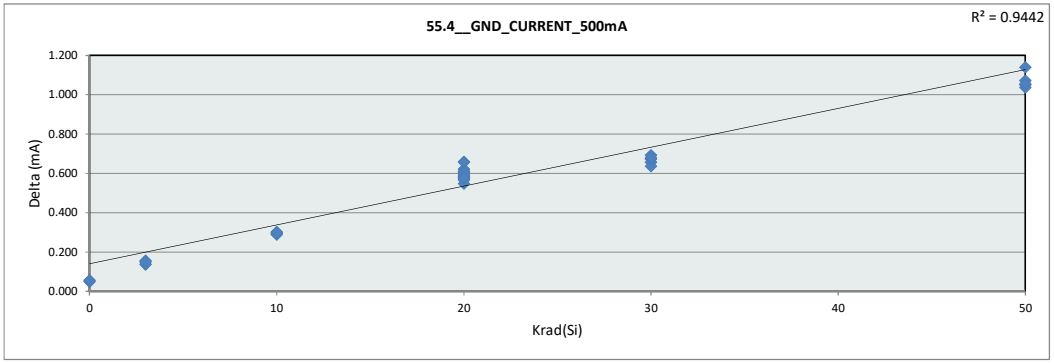
	55.3__GND_CURRENT_100mA					
Test Site						
Tester						
Test Number						
Max Limit	5.5	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	2.165	2.175	2.187	2.219	2.251	2.300
Average	2.169	2.186	2.195	2.248	2.265	2.330
Max	2.176	2.196	2.209	2.293	2.281	2.386
UL	5.500	5.500	5.500	5.500	5.500	5.500



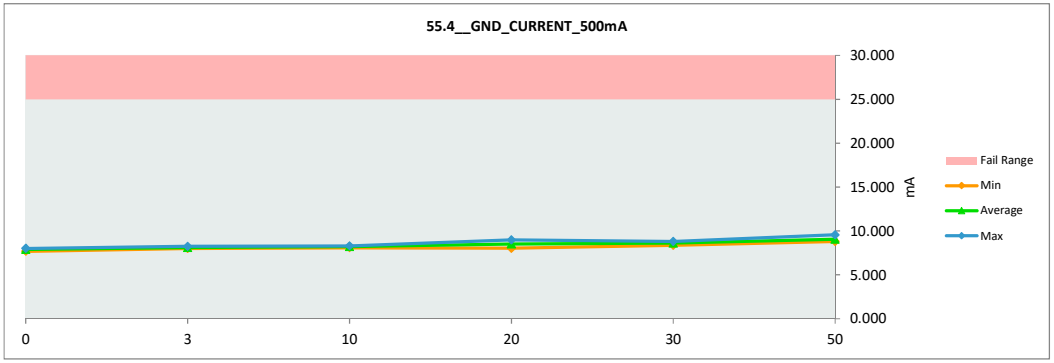
TID LDR Data (Biased)
TPS73801-SEP

	55.4__GND_CURRENT_500mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	25	25
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	7.946	7.996	0.049
0	69	7.633	7.686	0.053
0	70	7.958	8.015	0.057
3	1	7.928	8.068	0.139
3	2	7.940	8.077	0.137
3	3	7.833	7.986	0.154
3	4	7.979	8.135	0.156
3	5	8.086	8.235	0.149
10	11	7.995	8.286	0.292
10	12	7.880	8.177	0.297
10	13	7.784	8.086	0.302
10	14	8.005	8.295	0.289
10	15	7.959	8.259	0.299
20	41	7.597	8.166	0.569
20	42	7.905	8.497	0.592
20	43	8.100	8.680	0.581
20	44	7.814	8.397	0.583
20	45	7.810	8.393	0.583
20	46	8.081	8.686	0.605
20	47	8.043	8.662	0.620
20	48	7.989	8.597	0.609
20	49	7.441	8.018	0.577
20	50	7.960	8.528	0.568
20	51	7.610	8.158	0.548
20	52	7.958	8.564	0.606
20	53	7.908	8.509	0.600
20	54	7.790	8.388	0.598
20	55	8.107	8.729	0.622
20	56	8.217	8.874	0.657
20	57	7.908	8.517	0.609
20	58	8.024	8.625	0.601
20	59	7.905	8.483	0.578
20	60	8.332	8.991	0.658
20	61	7.958	8.540	0.581
20	62	7.860	8.436	0.576
30	21	7.953	8.611	0.658
30	22	8.108	8.801	0.693
30	23	7.725	8.363	0.637
30	24	7.941	8.615	0.674
30	25	7.939	8.618	0.679
50	31	8.418	9.558	1.141
50	32	7.828	8.901	1.073
50	33	7.761	8.799	1.038
50	34	7.893	8.948	1.055
50	35	8.099	9.150	1.051
Max		8.418	9.558	1.141
Average		7.931	8.469	0.538
Min		7.441	7.686	0.049
Std Dev		0.179	0.356	0.277



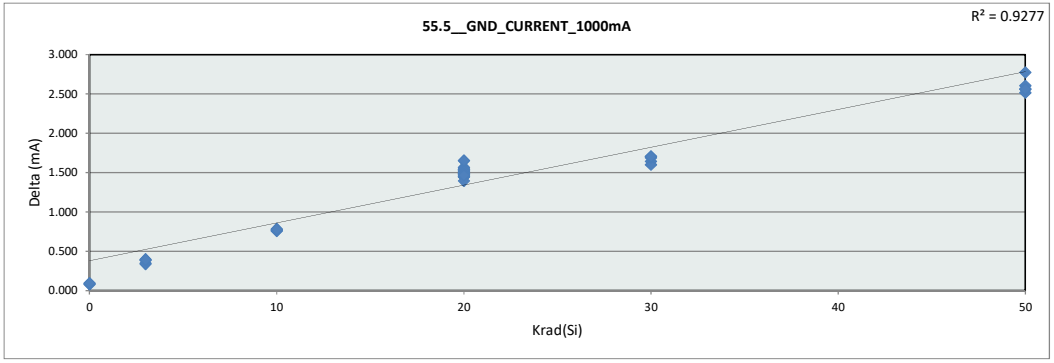
	55.4__GND_CURRENT_500mA					
Test Site						
Tester						
Test Number						
Max Limit	25	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	7.686	7.987	8.086	8.018	8.363	8.799
Average	7.899	8.100	8.221	8.520	8.601	9.071
Max	8.015	8.235	8.295	8.991	8.801	9.558
UL	25.000	25.000	25.000	25.000	25.000	25.000



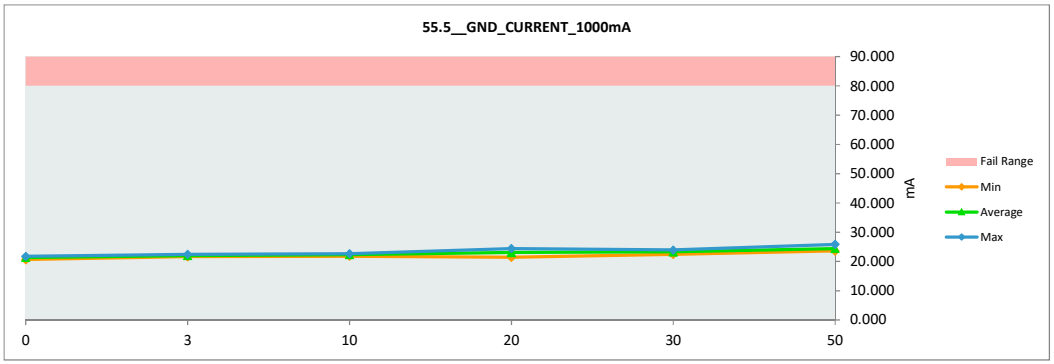
TID LDR Data (Biased)
TPS73801-SEP

	55.5__GND_CURRENT_1000mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	80	80
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	21.636	21.714	0.077
0	69	20.544	20.630	0.086
0	70	21.641	21.737	0.096
3	1	21.579	21.916	0.337
3	2	21.580	21.926	0.346
3	3	21.198	21.597	0.399
3	4	21.743	22.131	0.388
3	5	22.084	22.472	0.388
10	11	21.781	22.539	0.758
10	12	21.405	22.177	0.771
10	13	21.003	21.787	0.784
10	14	21.859	22.622	0.762
10	15	21.690	22.465	0.776
20	41	20.421	21.870	1.449
20	42	21.507	23.003	1.496
20	43	22.124	23.608	1.484
20	44	21.165	22.647	1.482
20	45	21.211	22.697	1.487
20	46	22.066	23.602	1.536
20	47	21.881	23.447	1.566
20	48	21.783	23.308	1.525
20	49	19.929	21.374	1.445
20	50	21.697	23.148	1.451
20	51	20.468	21.862	1.395
20	52	21.703	23.247	1.544
20	53	21.486	23.020	1.534
20	54	21.090	22.599	1.510
20	55	22.152	23.716	1.564
20	56	22.384	24.035	1.651
20	57	21.469	23.011	1.542
20	58	21.856	23.376	1.520
20	59	21.523	23.001	1.479
20	60	22.773	24.427	1.654
20	61	21.647	23.137	1.489
20	62	21.333	22.799	1.466
30	21	21.665	23.309	1.644
30	22	22.172	23.878	1.706
30	23	20.804	22.404	1.600
30	24	21.622	23.313	1.691
30	25	21.663	23.368	1.705
50	31	23.070	25.845	2.774
50	32	21.207	23.811	2.604
50	33	21.061	23.574	2.514
50	34	21.442	24.001	2.560
50	35	22.180	24.743	2.563
Max		23.070	25.845	2.774
Average		21.562	22.909	1.347
Min		19.929	20.630	0.077
Std Dev		0.585	0.974	0.680



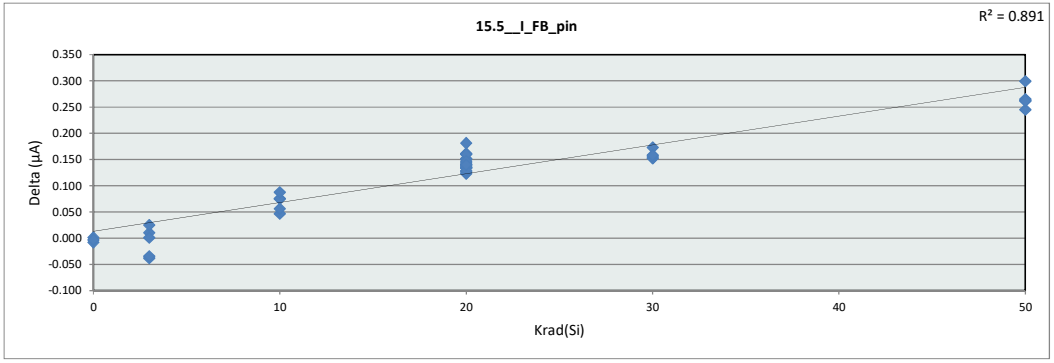
	55.5__GND_CURRENT_1000mA					
Test Site						
Tester						
Test Number						
Max Limit	80	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	20.630	21.597	21.787	21.374	22.404	23.575
Average	21.360	22.008	22.318	23.042	23.254	24.395
Max	21.737	22.472	22.622	24.427	23.878	25.845
UL	80.000	80.000	80.000	80.000	80.000	80.000



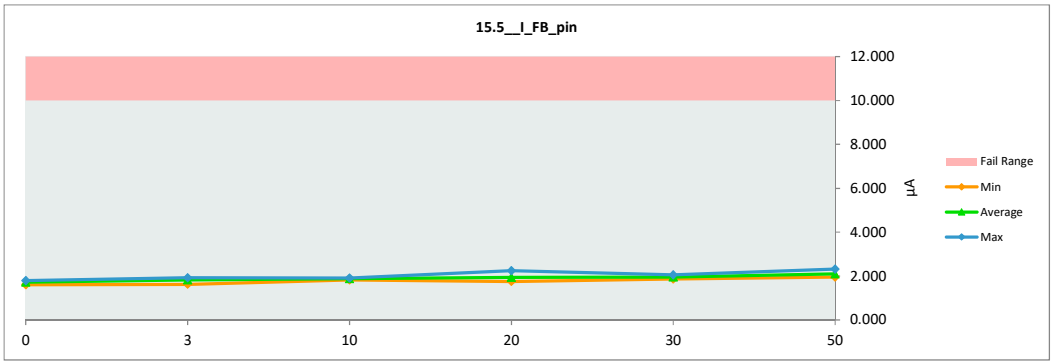
TID LDR Data (Biased)
TPS73801-SEP

	15.5__I_FB_pin	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	10	10
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.794	1.786	-0.008
0	69	1.607	1.608	0.001
0	70	1.792	1.789	-0.003
3	1	1.955	1.917	-0.038
3	2	1.939	1.905	-0.034
3	3	1.614	1.624	0.010
3	4	1.807	1.808	0.001
3	5	1.864	1.889	0.025
10	11	1.834	1.881	0.047
10	12	1.827	1.902	0.075
10	13	1.832	1.908	0.076
10	14	1.733	1.820	0.087
10	15	1.816	1.872	0.056
20	41	1.658	1.809	0.151
20	42	1.850	2.002	0.152
20	43	1.891	2.030	0.139
20	44	1.670	1.798	0.128
20	45	2.086	2.247	0.161
20	46	1.823	1.964	0.141
20	47	1.981	2.141	0.160
20	48	1.833	1.994	0.160
20	49	1.831	2.012	0.181
20	50	1.718	1.852	0.134
20	51	1.630	1.755	0.125
20	52	1.928	2.069	0.141
20	53	1.701	1.835	0.134
20	54	1.654	1.788	0.134
20	55	1.893	2.016	0.123
20	56	1.716	1.851	0.135
20	57	1.766	1.901	0.135
20	58	1.819	1.963	0.144
20	59	1.769	1.905	0.136
20	60	1.741	1.888	0.147
20	61	1.787	1.916	0.129
20	62	1.806	1.947	0.140
30	21	1.838	1.991	0.153
30	22	1.878	2.051	0.173
30	23	1.714	1.867	0.153
30	24	1.824	1.981	0.156
30	25	1.741	1.899	0.158
50	31	1.741	1.986	0.245
50	32	1.695	1.958	0.263
50	33	2.018	2.318	0.299
50	34	1.798	2.064	0.265
50	35	1.903	2.164	0.262
Max		2.086	2.318	0.299
Average		1.803	1.926	0.123
Min		1.607	1.608	-0.038
Std Dev		0.105	0.138	0.079



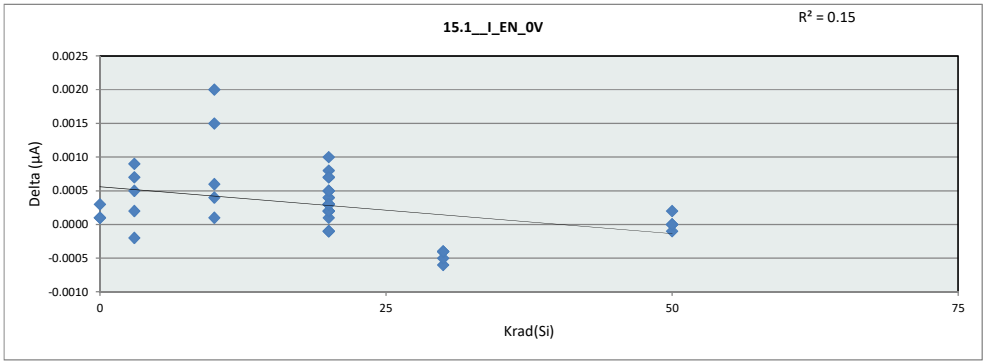
	15.5__I_FB_pin					
Test Site						
Tester						
Test Number						
Max Limit	10	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.608	1.624	1.820	1.755	1.867	1.958
Average	1.727	1.828	1.877	1.940	1.958	2.098
Max	1.789	1.917	1.908	2.247	2.051	2.318
UL	10.000	10.000	10.000	10.000	10.000	10.000



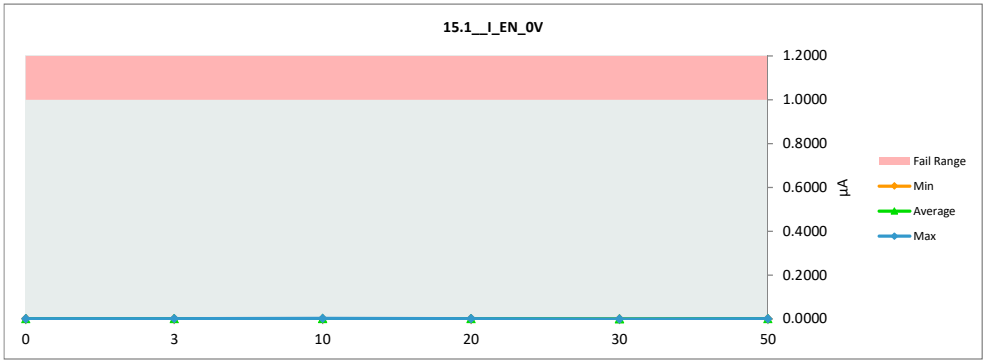
TID LDR Data (Biased)
TPS73801-SEP

	15.1__I_EN_0V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	1	1
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.0011	0.0012	0.0001
0	69	0.0009	0.0012	0.0003
0	70	0.0012	0.0013	0.0001
3	1	0.0010	0.0015	0.0005
3	2	0.0011	0.0013	0.0002
3	3	0.0008	0.0015	0.0007
3	4	0.0010	0.0019	0.0009
3	5	0.0012	0.0010	-0.0002
10	11	0.0011	0.0012	0.0001
10	12	0.0010	0.0030	0.0020
10	13	0.0007	0.0013	0.0006
10	14	0.0008	0.0023	0.0015
10	15	0.0009	0.0013	0.0004
20	41	0.0009	0.0011	0.0002
20	42	0.0012	0.0011	-0.0001
20	43	0.0010	0.0012	0.0002
20	44	0.0009	0.0013	0.0004
20	45	0.0010	0.0011	0.0001
20	46	0.0010	0.0013	0.0003
20	47	0.0011	0.0013	0.0002
20	48	0.0007	0.0012	0.0005
20	49	0.0009	0.0012	0.0003
20	50	0.0007	0.0011	0.0004
20	51	0.0011	0.0013	0.0002
20	52	0.0003	0.0010	0.0007
20	53	0.0004	0.0014	0.0010
20	54	0.0009	0.0012	0.0003
20	55	0.0008	0.0013	0.0005
20	56	0.0009	0.0014	0.0005
20	57	0.0008	0.0016	0.0008
20	58	0.0010	0.0013	0.0003
20	59	0.0013	0.0012	-0.0001
20	60	0.0007	0.0014	0.0007
20	61	0.0010	0.0013	0.0003
20	62	0.0011	0.0010	-0.0001
30	21	0.0009	0.0003	-0.0006
30	22	0.0008	0.0004	-0.0004
30	23	0.0009	0.0004	-0.0005
30	24	0.0009	0.0005	-0.0004
30	25	0.0008	0.0004	-0.0004
50	31	0.0008	0.0010	0.0002
50	32	0.0010	0.0010	0.0000
50	33	0.0011	0.0011	0.0000
50	34	0.0009	0.0008	-0.0001
50	35	0.0009	0.0009	0.0000
Max		0.0013	0.0030	0.0020
Average		0.0009	0.0012	0.0003
Min		0.0003	0.0003	-0.0006
Std Dev		0.0002	0.0005	0.0005



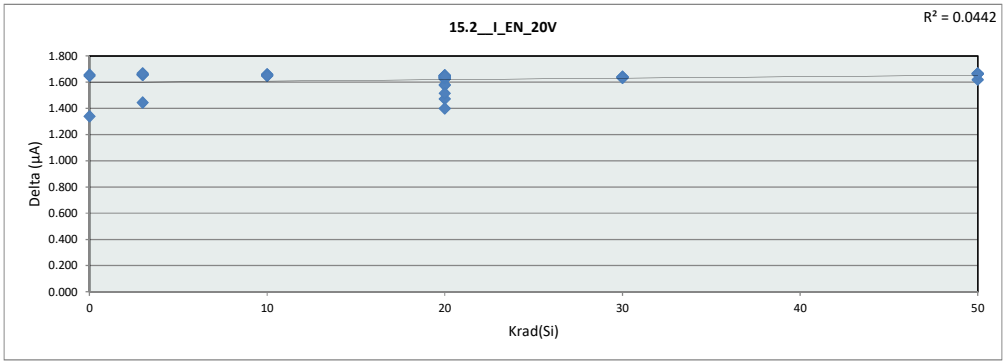
	15.1__I_EN_0V					
Test Site						
Tester						
Test Number						
Max Limit	1	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.0012	0.0010	0.0012	0.0010	0.0003	0.0008
Average	0.0012	0.0014	0.0018	0.0012	0.0004	0.0010
Max	0.0013	0.0019	0.0030	0.0016	0.0005	0.0011
UL	1.0000	1.0000	1.0000	1.0000	1.0000	1.0000



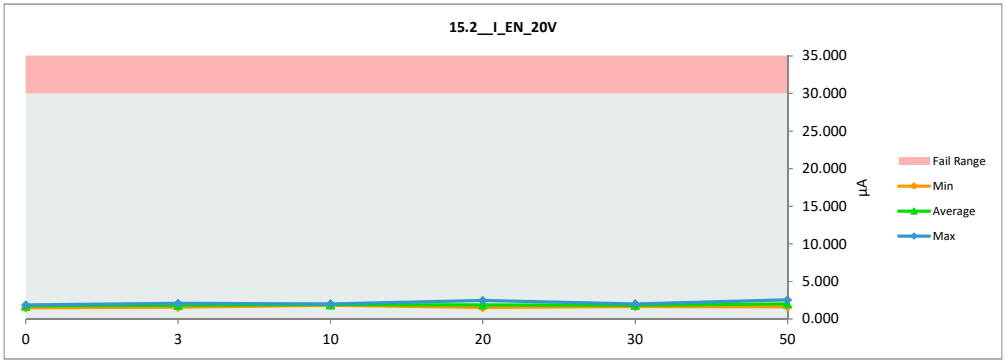
TID LDR Data (Biased)
TPS73801-SEP

	15.2__I_EN_20V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	30	30
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.218	1.874	1.656
0	69	0.158	1.496	1.339
0	70	0.173	1.822	1.648
3	1	0.128	1.786	1.658
3	2	0.103	1.760	1.657
3	3	0.108	1.552	1.444
3	4	0.237	1.892	1.656
3	5	0.405	2.073	1.668
10	11	0.157	1.817	1.659
10	12	0.337	1.990	1.653
10	13	0.363	2.021	1.658
10	14	0.181	1.832	1.651
10	15	0.235	1.884	1.649
20	41	0.086	1.558	1.472
20	42	0.316	1.960	1.644
20	43	0.530	2.167	1.637
20	44	0.034	1.615	1.580
20	45	0.816	2.448	1.632
20	46	0.438	2.084	1.647
20	47	0.760	2.390	1.629
20	48	0.253	1.903	1.649
20	49	0.464	2.116	1.653
20	50	0.116	1.768	1.651
20	51	0.126	1.525	1.399
20	52	0.582	2.208	1.625
20	53	0.010	1.634	1.624
20	54	0.037	1.613	1.576
20	55	0.527	2.158	1.631
20	56	0.060	1.576	1.515
20	57	0.139	1.784	1.645
20	58	0.199	1.847	1.648
20	59	0.138	1.776	1.638
20	60	0.004	1.640	1.635
20	61	0.149	1.785	1.635
20	62	0.239	1.883	1.644
30	21	0.261	1.899	1.638
30	22	0.386	2.024	1.637
30	23	0.011	1.652	1.642
30	24	0.250	1.883	1.632
30	25	0.138	1.774	1.636
50	31	0.027	1.692	1.665
50	32	0.023	1.642	1.619
50	33	0.868	2.535	1.667
50	34	0.171	1.835	1.664
50	35	0.684	2.346	1.662
Max		0.868	2.535	1.668
Average		0.259	1.878	1.619
Min		0.004	1.496	1.339
Std Dev		0.222	0.250	0.072



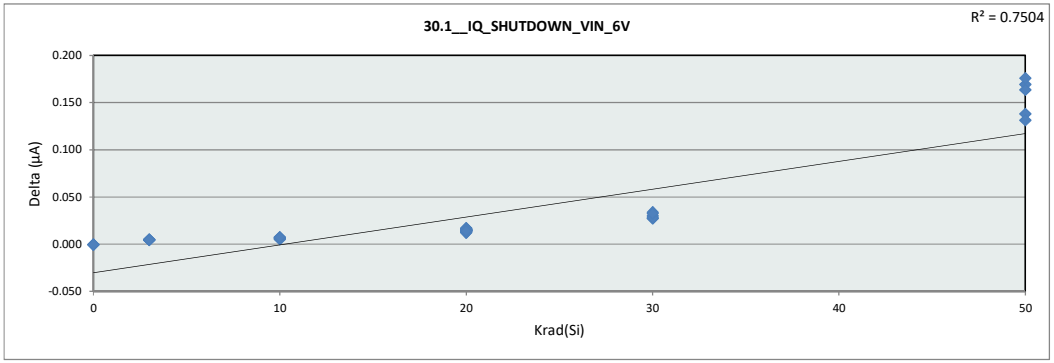
	15.2__I_EN_20V					
Test Site						
Tester						
Test Number						
Max Limit	30	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.496	1.552	1.817	1.525	1.652	1.642
Average	1.731	1.813	1.909	1.883	1.846	2.010
Max	1.874	2.073	2.021	2.448	2.024	2.535
UL	30.000	30.000	30.000	30.000	30.000	30.000



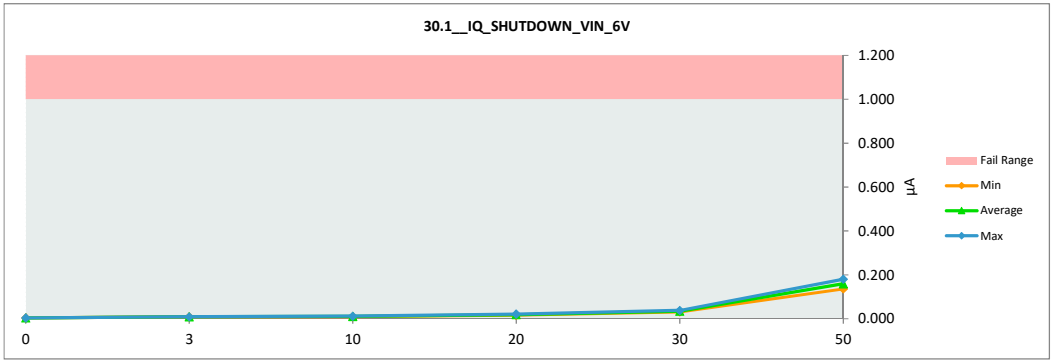
TID LDR Data (Biased)
TPS73801-SEP

	30.1__IQ_SHUTDOWN_VIN_6V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	1	1
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.004	0.004	-0.001
0	69	0.004	0.004	0.000
0	70	0.004	0.004	-0.001
3	1	0.004	0.009	0.005
3	2	0.004	0.009	0.005
3	3	0.004	0.009	0.005
3	4	0.004	0.009	0.005
3	5	0.004	0.009	0.005
10	11	0.004	0.010	0.006
10	12	0.004	0.009	0.005
10	13	0.004	0.010	0.006
10	14	0.004	0.011	0.007
10	15	0.004	0.011	0.007
20	41	0.004	0.020	0.016
20	42	0.004	0.017	0.012
20	43	0.004	0.019	0.015
20	44	0.004	0.019	0.014
20	45	0.004	0.021	0.017
20	46	0.004	0.019	0.014
20	47	0.004	0.016	0.012
20	48	0.004	0.019	0.015
20	49	0.004	0.021	0.017
20	50	0.004	0.019	0.015
20	51	0.004	0.019	0.015
20	52	0.005	0.020	0.015
20	53	0.004	0.019	0.015
20	54	0.004	0.019	0.015
20	55	0.004	0.018	0.014
20	56	0.004	0.019	0.015
20	57	0.004	0.017	0.013
20	58	0.004	0.020	0.016
20	59	0.004	0.020	0.016
20	60	0.004	0.019	0.015
20	61	0.004	0.017	0.013
20	62	0.004	0.018	0.014
30	21	0.004	0.031	0.027
30	22	0.004	0.034	0.030
30	23	0.004	0.032	0.028
30	24	0.004	0.038	0.034
30	25	0.004	0.037	0.032
50	31	0.004	0.142	0.138
50	32	0.004	0.173	0.169
50	33	0.004	0.135	0.131
50	34	0.004	0.180	0.176
50	35	0.004	0.168	0.164
Max		0.005	0.180	0.176
Average		0.004	0.033	0.029
Min		0.004	0.004	-0.001
Std Dev		0.000	0.046	0.046



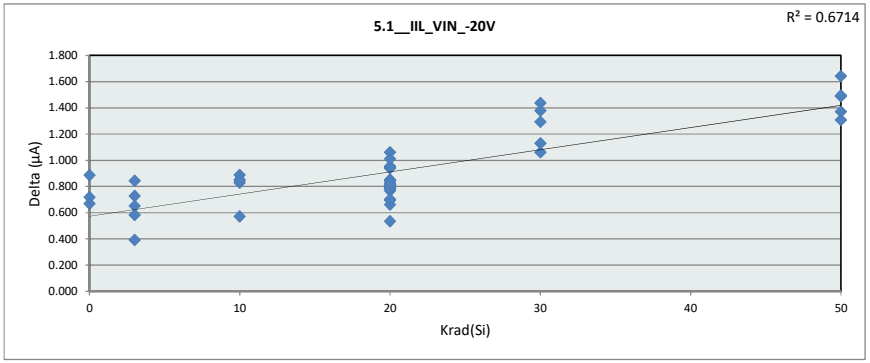
	30.1__IQ_SHUTDOWN_VIN_6V					
Test Site						
Tester						
Test Number						
Max Limit	1	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.004	0.009	0.009	0.016	0.031	0.136
Average	0.004	0.009	0.010	0.019	0.034	0.160
Max	0.004	0.009	0.011	0.021	0.038	0.180
UL	1.000	1.000	1.000	1.000	1.000	1.000



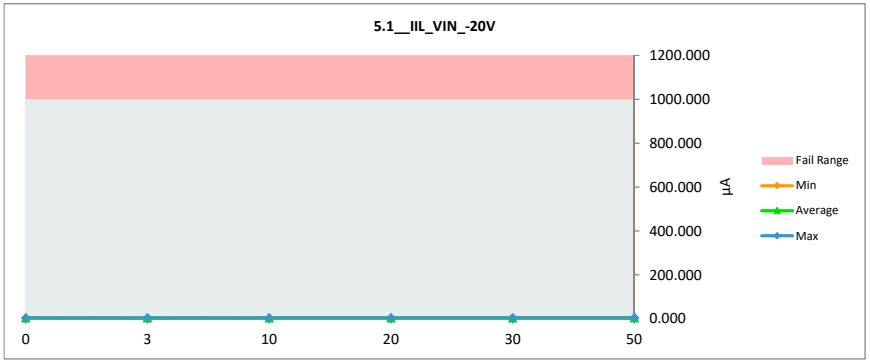
TID LDR Data (Biased)
TPS73801-SEP

	5.1__IIL_VIN_-20V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	1000	1000
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	2.185	2.903	0.718
0	69	2.152	3.039	0.888
0	70	2.208	2.879	0.671
3	1	2.264	2.658	0.394
3	2	2.120	2.849	0.729
3	3	2.050	2.895	0.845
3	4	2.294	2.947	0.653
3	5	2.190	2.774	0.584
10	11	2.235	2.807	0.572
10	12	2.217	3.047	0.829
10	13	2.138	2.992	0.854
10	14	2.074	2.962	0.888
10	15	2.168	3.013	0.846
20	41	2.405	3.175	0.770
20	42	2.302	3.244	0.942
20	43	2.487	3.330	0.843
20	44	2.303	3.074	0.770
20	45	2.436	3.251	0.815
20	46	2.521	3.056	0.535
20	47	2.460	3.254	0.794
20	48	2.421	3.116	0.696
20	49	2.443	3.250	0.807
20	50	2.458	3.272	0.814
20	51	2.501	3.164	0.662
20	52	2.242	3.303	1.061
20	53	2.357	3.142	0.785
20	54	2.187	3.142	0.955
20	55	2.214	3.156	0.942
20	56	2.303	3.111	0.807
20	57	2.208	3.062	0.853
20	58	2.359	3.208	0.849
20	59	2.236	3.247	1.011
20	60	2.324	3.026	0.702
20	61	2.339	3.129	0.789
20	62	2.413	3.238	0.825
30	21	2.253	3.382	1.130
30	22	2.140	3.577	1.438
30	23	2.310	3.689	1.379
30	24	2.245	3.540	1.294
30	25	2.329	3.391	1.062
50	31	2.141	3.783	1.642
50	32	2.382	3.691	1.309
50	33	2.163	3.652	1.488
50	34	2.248	3.619	1.371
50	35	2.278	3.773	1.495
Max		2.521	3.783	1.642
Average		2.282	3.196	0.914
Min		2.050	2.658	0.394
Std Dev		0.119	0.274	0.281



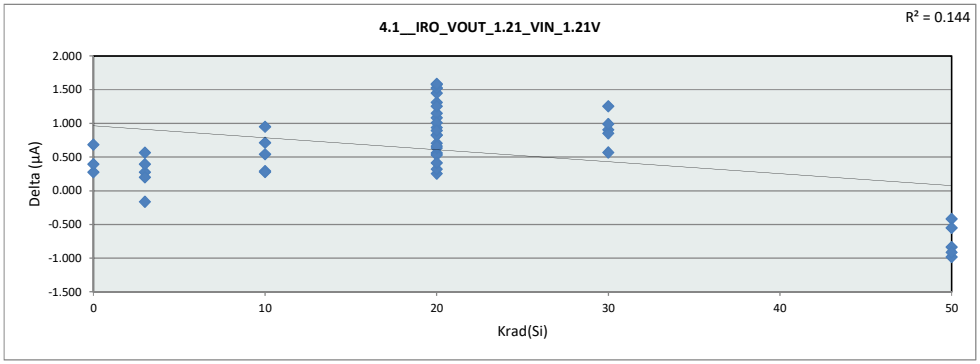
	5.1__IIL_VIN_-20V					
Test Site						
Tester						
Test Number						
Max Limit	1000	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	2.879	2.658	2.807	3.026	3.382	3.619
Average	2.940	2.825	2.964	3.180	3.516	3.704
Max	3.039	2.947	3.047	3.330	3.689	3.784
UL	1000.000	1000.000	1000.000	1000.000	1000.000	1000.000



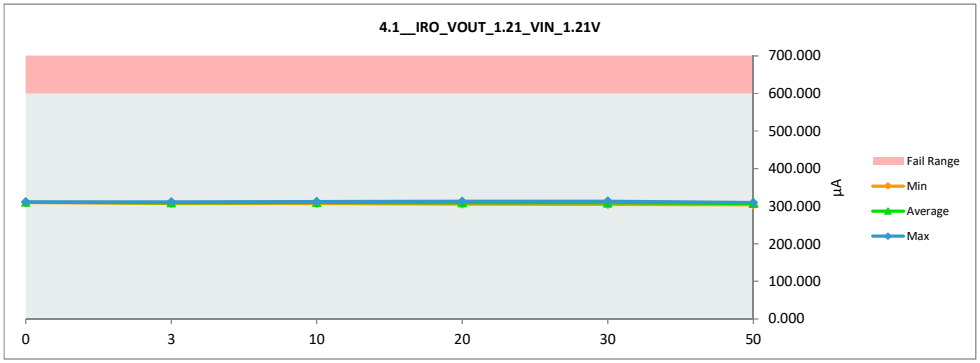
TID LDR Data (Biased)
TPS73801-SEP

	4.1__IRO_VOUT_1.21_VIN_1.21	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	600	600
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	309.297	309.573	0.275
0	69	311.463	311.858	0.395
0	70	309.543	310.229	0.686
3	1	308.286	308.562	0.276
3	2	307.015	307.215	0.200
3	3	311.105	311.501	0.396
3	4	308.979	309.544	0.565
3	5	309.689	309.524	-0.165
10	11	309.660	309.952	0.292
10	12	309.011	309.554	0.543
10	13	311.958	312.237	0.279
10	14	306.509	307.223	0.714
10	15	308.262	309.213	0.952
20	41	312.109	313.194	1.085
20	42	307.642	308.471	0.829
20	43	306.407	307.556	1.149
20	44	308.148	308.710	0.561
20	45	304.930	306.244	1.313
20	46	306.608	307.313	0.705
20	47	305.935	307.386	1.451
20	48	308.118	308.651	0.533
20	49	310.627	310.882	0.255
20	50	305.400	305.723	0.322
20	51	311.345	311.761	0.416
20	52	305.213	306.739	1.526
20	53	308.855	309.795	0.940
20	54	307.615	308.249	0.634
20	55	307.076	308.600	1.524
20	56	310.298	311.876	1.578
20	57	309.161	309.987	0.826
20	58	309.222	309.884	0.662
20	59	307.672	308.926	1.255
20	60	307.322	308.331	1.010
20	61	309.171	310.758	1.587
20	62	309.862	310.755	0.893
30	21	305.715	306.620	0.905
30	22	305.543	306.396	0.853
30	23	313.124	313.691	0.568
30	24	309.535	310.791	1.256
30	25	303.666	304.657	0.991
50	31	310.227	309.810	-0.417
50	32	307.830	306.848	-0.982
50	33	304.994	304.157	-0.837
50	34	310.389	309.475	-0.914
50	35	305.731	305.180	-0.551
	Max	313.124	313.691	1.587
	Average	308.361	308.969	0.607
	Min	303.666	304.157	-0.982
	Std Dev	2.200	2.202	0.638



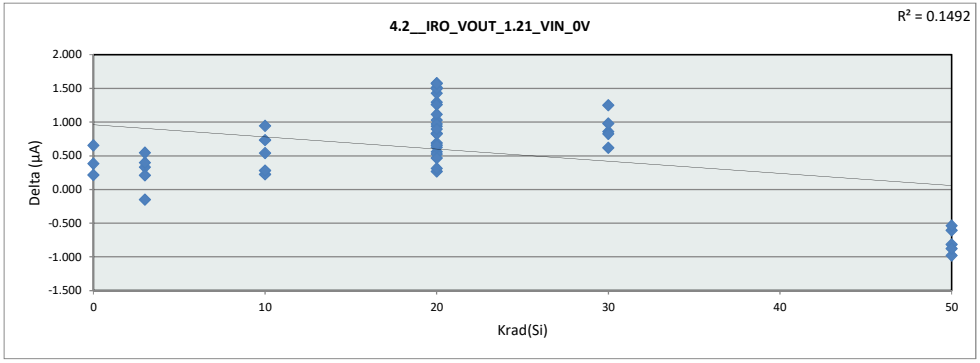
	4.1__IRO_VOUT_1.21_VIN_1.2					
Test Site						
Tester						
Test Number						
Max Limit	600	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	309.573	307.215	307.223	305.723	304.657	304.157
Average	310.553	309.269	309.636	309.081	308.431	307.094
Max	311.858	311.501	312.237	313.194	313.691	309.810
UL	600.000	600.000	600.000	600.000	600.000	600.000



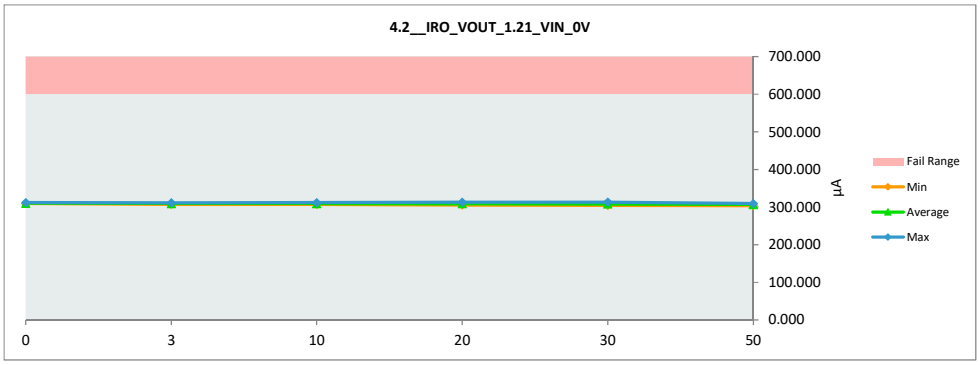
TID LDR Data (Biased)
TPS73801-SEP

	4.2__IRO_VOUT_1.21_VIN_0V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	600	600
Min Limit		

Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	309.040	309.255	0.215
0	69	311.210	311.591	0.382
0	70	309.290	309.941	0.652
3	1	307.935	308.266	0.331
3	2	306.735	306.945	0.210
3	3	310.831	311.227	0.396
3	4	308.707	309.251	0.544
3	5	309.412	309.260	-0.152
10	11	309.403	309.627	0.224
10	12	308.743	309.281	0.538
10	13	311.691	311.971	0.280
10	14	306.218	306.951	0.733
10	15	307.988	308.930	0.942
20	41	311.843	312.872	1.029
20	42	307.365	308.196	0.831
20	43	306.149	307.264	1.115
20	44	307.888	308.446	0.558
20	45	304.666	305.960	1.294
20	46	306.354	307.044	0.691
20	47	305.676	307.103	1.427
20	48	307.857	308.382	0.525
20	49	310.357	310.622	0.266
20	50	305.144	305.455	0.311
20	51	311.032	311.496	0.464
20	52	304.947	306.456	1.510
20	53	308.593	309.531	0.938
20	54	307.355	307.980	0.625
20	55	306.827	308.320	1.493
20	56	310.030	311.607	1.577
20	57	308.899	309.721	0.823
20	58	308.948	309.603	0.655
20	59	307.398	308.657	1.259
20	60	307.089	308.061	0.972
20	61	308.916	310.485	1.569
20	62	309.598	310.492	0.894
30	21	305.449	306.306	0.857
30	22	305.297	306.120	0.823
30	23	312.770	313.389	0.618
30	24	309.268	310.515	1.247
30	25	303.394	304.373	0.979
50	31	309.976	309.371	-0.605
50	32	307.566	306.587	-0.979
50	33	304.717	303.900	-0.817
50	34	310.098	309.221	-0.877
50	35	305.462	304.925	-0.537
	Max	312.770	313.389	1.577
	Average	308.092	308.688	0.596
	Min	303.394	303.900	-0.979
	Std Dev	2.194	2.198	0.635



	4.2__IRO_VOUT_1.21_VIN_0V					
Test Site						
Tester						
Test Number						
Max Limit	600	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	309.255	306.945	306.951	305.455	304.373	303.900
Average	310.263	308.990	309.352	308.807	308.141	306.801
Max	311.591	311.227	311.971	312.872	313.389	309.371
UL	600.000	600.000	600.000	600.000	600.000	600.000

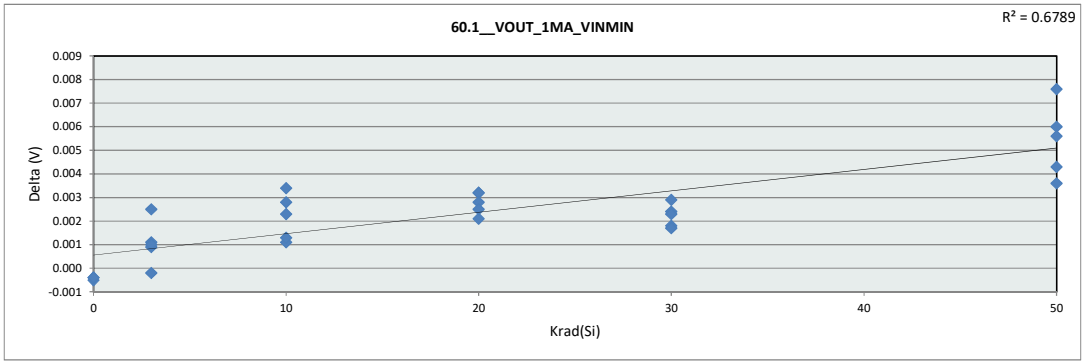


TID LDR Data - UNBIASED
TPS73801-SEP

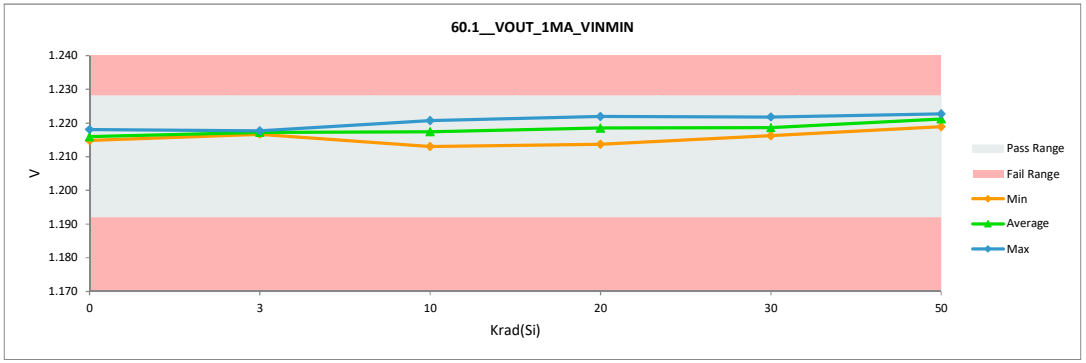
TID LDR Data (Unbiased)
TPS73801-SEP

	60.1__VOUT_1MA_VINMIN	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.228	1.228
Min Limit	1.192	1.192

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.215	1.215	0.000
0	69	1.219	1.218	0.000
0	70	1.215	1.215	0.000
3	6	1.216	1.217	0.001
3	7	1.216	1.217	0.001
3	8	1.218	1.218	0.000
3	9	1.216	1.217	0.001
3	10	1.215	1.218	0.002
10	16	1.212	1.213	0.001
10	17	1.219	1.220	0.001
10	18	1.213	1.216	0.003
10	19	1.217	1.221	0.003
10	20	1.215	1.218	0.002
20	63	1.216	1.220	0.003
20	64	1.219	1.222	0.003
20	65	1.212	1.214	0.002
20	66	1.216	1.219	0.003
20	67	1.215	1.218	0.003
30	26	1.216	1.218	0.002
30	27	1.215	1.218	0.002
30	28	1.220	1.222	0.002
30	29	1.217	1.219	0.002
30	30	1.213	1.216	0.003
50	36	1.216	1.222	0.006
50	37	1.217	1.221	0.004
50	38	1.218	1.222	0.004
50	39	1.215	1.223	0.008
50	40	1.213	1.219	0.006
Max		1.220	1.223	0.008
Average		1.216	1.218	0.002
Min		1.212	1.213	0.000
Std Dev		0.002	0.003	0.002



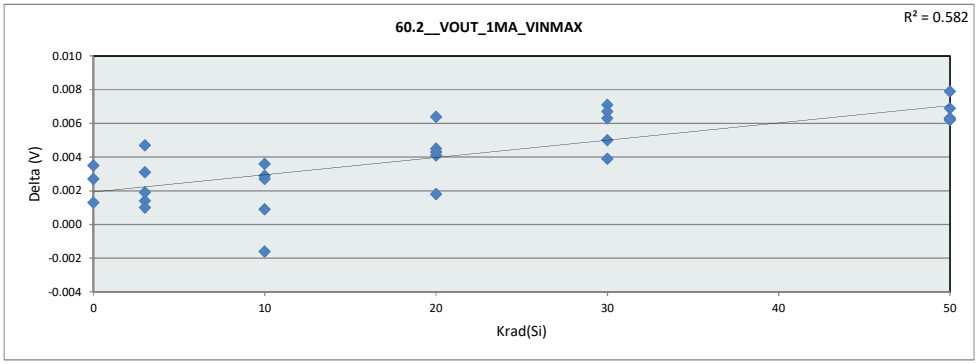
	60.1__VOUT_1MA_VINMIN					
Test Site						
Tester						
Test Number						
Max Limit	1.228	V				
Min Limit	1.192	V				
Krad(Si)	0	3	10	20	30	50
LL	1.192	1.192	1.192	1.192	1.192	1.192
Min	1.215	1.217	1.213	1.214	1.216	1.219
Average	1.216	1.217	1.217	1.218	1.219	1.221
Max	1.218	1.218	1.221	1.222	1.222	1.223
UL	1.228	1.228	1.228	1.228	1.228	1.228



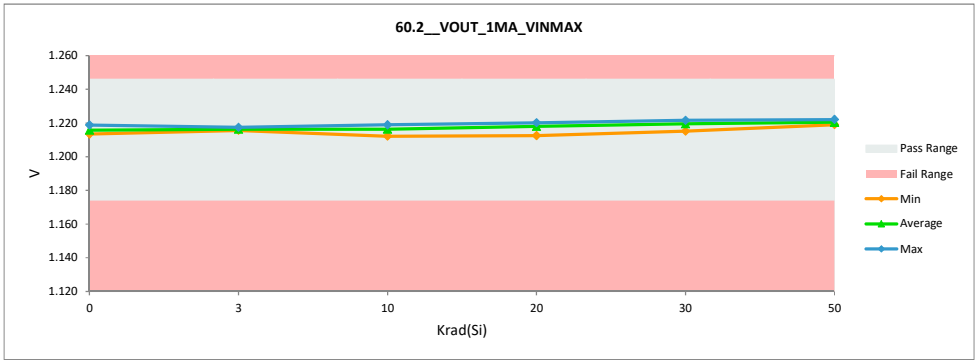
TID LDR Data (Unbiased)
TPS73801-SEP

	60.2__VOUT_1MA_VINMAX	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.212	1.214	0.001
0	69	1.216	1.219	0.003
0	70	1.211	1.215	0.003
3	6	1.213	1.216	0.003
3	7	1.213	1.217	0.005
3	8	1.216	1.217	0.001
3	9	1.214	1.216	0.002
3	10	1.215	1.216	0.001
10	16	1.214	1.212	-0.002
10	17	1.218	1.219	0.001
10	18	1.212	1.215	0.003
10	19	1.215	1.219	0.004
10	20	1.214	1.217	0.003
20	63	1.215	1.220	0.004
20	64	1.218	1.220	0.002
20	65	1.208	1.213	0.005
20	66	1.216	1.220	0.004
20	67	1.212	1.218	0.006
30	26	1.214	1.220	0.006
30	27	1.213	1.220	0.007
30	28	1.217	1.222	0.005
30	29	1.214	1.220	0.007
30	30	1.211	1.215	0.004
50	36	1.215	1.222	0.007
50	37	1.214	1.220	0.006
50	38	1.215	1.221	0.006
50	39	1.214	1.220	0.006
50	40	1.211	1.219	0.008
	Max	1.218	1.222	0.008
	Average	1.214	1.218	0.004
	Min	1.208	1.212	-0.002
	Std Dev	0.002	0.003	0.002



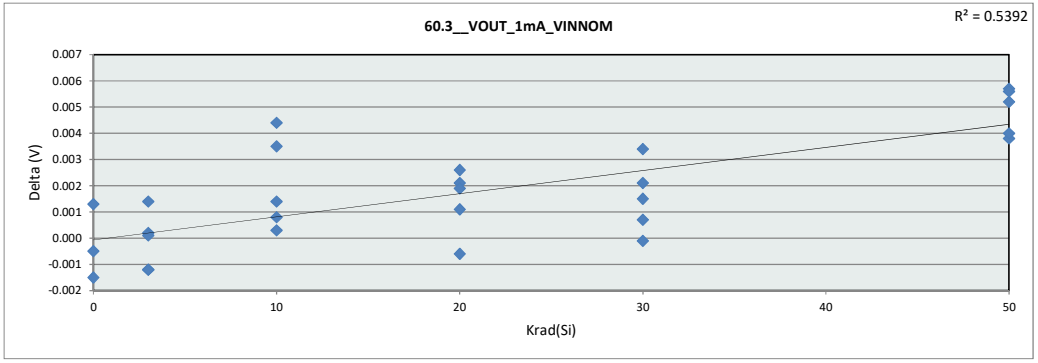
	60.2__VOUT_1MA_VINMAX					
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.214	1.216	1.212	1.213	1.215	1.219
Average	1.216	1.216	1.216	1.218	1.220	1.220
Max	1.219	1.218	1.219	1.220	1.222	1.222
UL	1.246	1.246	1.246	1.246	1.246	1.246



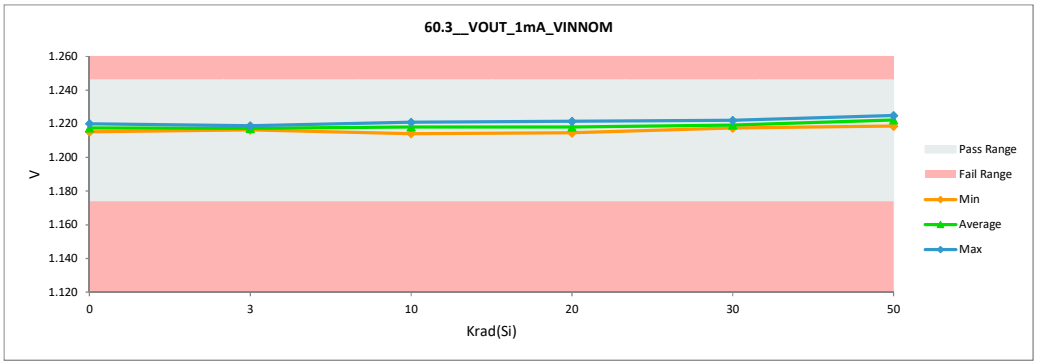
TID LDR Data (Unbiased)
TPS73801-SEP

	60.3__VOUT_1mA_VINNOM	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.217	1.215	-0.001
0	69	1.219	1.220	0.001
0	70	1.218	1.217	0.000
3	6	1.218	1.217	-0.001
3	7	1.217	1.217	0.000
3	8	1.217	1.219	0.001
3	9	1.217	1.216	-0.001
3	10	1.217	1.217	0.000
10	16	1.214	1.214	0.000
10	17	1.219	1.221	0.001
10	18	1.213	1.217	0.004
10	19	1.217	1.220	0.003
10	20	1.217	1.218	0.001
20	63	1.217	1.219	0.003
20	64	1.219	1.221	0.002
20	65	1.213	1.215	0.002
20	66	1.217	1.218	0.001
20	67	1.217	1.217	-0.001
30	26	1.217	1.218	0.001
30	27	1.217	1.219	0.002
30	28	1.220	1.222	0.002
30	29	1.220	1.220	0.000
30	30	1.214	1.217	0.003
50	36	1.217	1.223	0.006
50	37	1.219	1.222	0.004
50	38	1.220	1.225	0.005
50	39	1.217	1.222	0.006
50	40	1.215	1.219	0.004
	Max	1.220	1.225	0.006
	Average	1.217	1.219	0.002
	Min	1.213	1.214	-0.001
	Std Dev	0.002	0.003	0.002



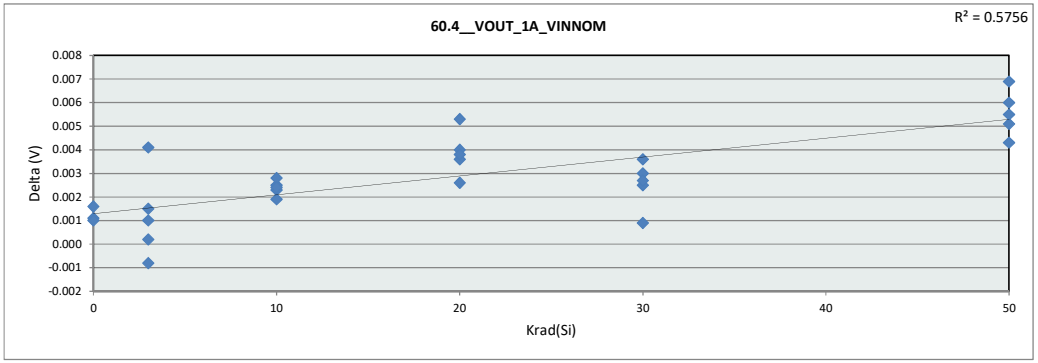
	60.3__VOUT_1mA_VINNOM					
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.216	1.214	1.215	1.217	1.219
Average	1.218	1.217	1.218	1.218	1.219	1.222
Max	1.220	1.219	1.221	1.221	1.222	1.225
UL	1.246	1.246	1.246	1.246	1.246	1.246



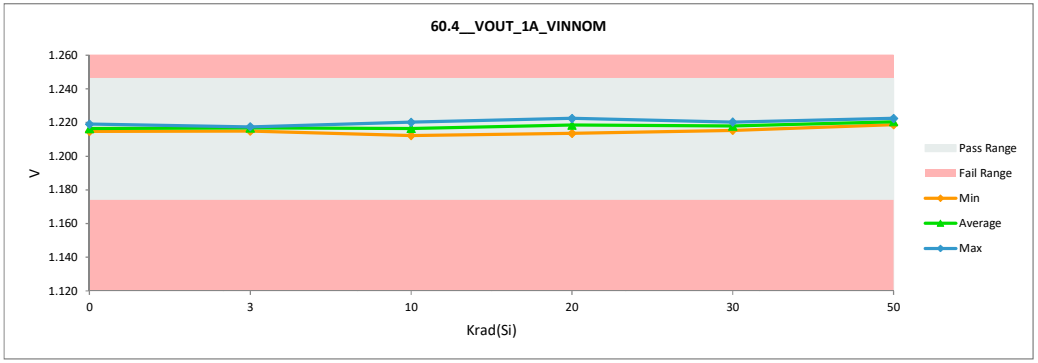
TID LDR Data (Unbiased)
TPS73801-SEP

	60.4__VOUT_1A_VINNOM	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.214	1.215	0.002
0	69	1.218	1.219	0.001
0	70	1.214	1.215	0.001
3	6	1.217	1.217	0.000
3	7	1.215	1.217	0.002
3	8	1.218	1.217	-0.001
3	9	1.214	1.215	0.001
3	10	1.213	1.217	0.004
10	16	1.210	1.212	0.002
10	17	1.218	1.220	0.002
10	18	1.211	1.214	0.003
10	19	1.217	1.219	0.002
10	20	1.215	1.217	0.002
20	63	1.216	1.219	0.004
20	64	1.217	1.222	0.005
20	65	1.211	1.214	0.003
20	66	1.215	1.219	0.004
20	67	1.214	1.218	0.004
30	26	1.215	1.218	0.003
30	27	1.214	1.218	0.004
30	28	1.219	1.220	0.001
30	29	1.216	1.219	0.003
30	30	1.213	1.215	0.003
50	36	1.216	1.221	0.005
50	37	1.214	1.219	0.004
50	38	1.217	1.222	0.005
50	39	1.214	1.221	0.007
50	40	1.213	1.219	0.006
Max		1.219	1.222	0.007
Average		1.215	1.218	0.003
Min		1.210	1.212	-0.001
Std Dev		0.002	0.003	0.002



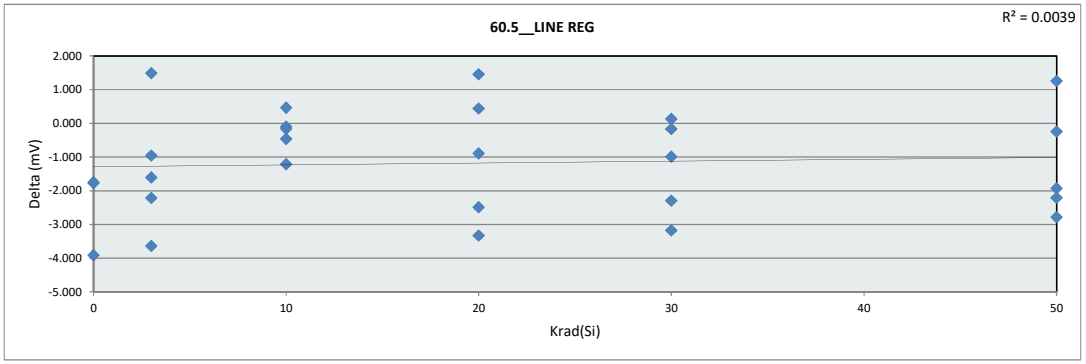
	60.4__VOUT_1A_VINNOM					
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.215	1.212	1.214	1.215	1.219
Average	1.216	1.217	1.216	1.218	1.218	1.220
Max	1.219	1.218	1.220	1.223	1.220	1.222
UL	1.246	1.246	1.246	1.246	1.246	1.246



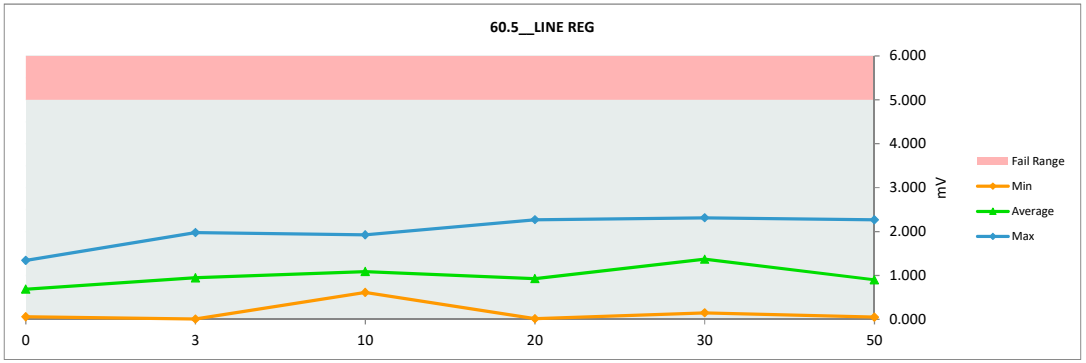
TID LDR Data (Unbiased)
TPS73801-SEP

	60.5__LINE REG	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	5	5
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	3.112	1.342	-1.771
0	69	2.410	0.666	-1.744
0	70	3.971	0.060	-3.912
3	6	3.263	1.048	-2.215
3	7	3.643	0.006	-3.637
3	8	2.354	0.748	-1.606
3	9	1.902	0.950	-0.952
3	10	0.488	1.977	1.489
10	16	1.944	0.734	-1.210
10	17	0.860	1.325	0.465
10	18	0.946	0.850	-0.096
10	19	2.090	1.927	-0.163
10	20	1.071	0.615	-0.456
20	63	0.905	0.015	-0.890
20	64	0.814	2.272	1.458
20	65	3.569	1.085	-2.484
20	66	0.557	0.998	0.441
20	67	3.606	0.278	-3.328
30	26	1.894	2.031	0.137
30	27	2.480	2.312	-0.168
30	28	3.322	0.148	-3.174
30	29	3.666	1.372	-2.294
30	30	1.976	0.988	-0.988
50	36	0.607	0.365	-0.242
50	37	3.013	1.084	-1.929
50	38	3.533	0.751	-2.781
50	39	1.011	2.267	1.256
50	40	2.253	0.048	-2.205
	Max	3.971	2.312	1.489
	Average	2.188	1.009	-1.179
	Min	0.488	0.006	-3.912
	Std Dev	1.141	0.722	1.528



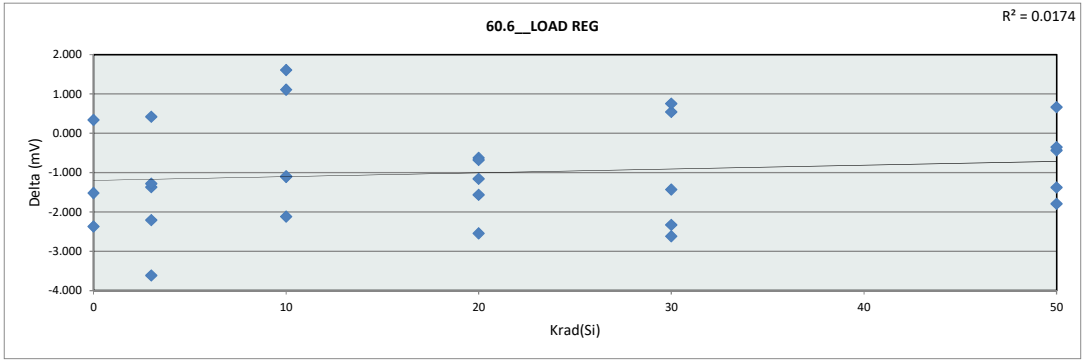
	60.5__LINE REG					
Test Site						
Tester						
Test Number						
Max Limit	5	mV				
Min Limit		mV				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.060	0.006	0.615	0.015	0.148	0.048
Average	0.689	0.946	1.090	0.930	1.370	0.903
Max	1.342	1.978	1.927	2.272	2.312	2.267
UL	5.000	5.000	5.000	5.000	5.000	5.000



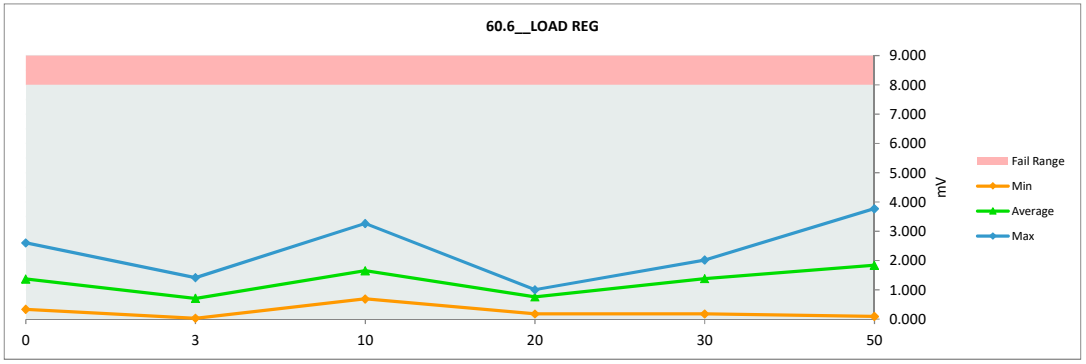
TID LDR Data (Unbiased)
TPS73801-SEP

	60.6__LOAD REG	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	8	8
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	2.708	0.338	-2.370
0	69	0.831	1.174	0.343
0	70	4.126	2.607	-1.518
3	6	1.402	0.033	-1.369
3	7	1.879	0.597	-1.282
3	8	0.885	1.304	0.419
3	9	3.624	1.416	-2.209
3	10	3.803	0.191	-3.613
10	16	3.881	1.762	-2.119
10	17	1.802	0.692	-1.110
10	18	1.657	3.270	1.613
10	19	0.495	1.601	1.106
10	20	2.039	0.946	-1.093
20	63	0.806	0.181	-0.625
20	64	2.165	1.007	-1.158
20	65	1.678	0.998	-0.681
20	66	2.261	0.700	-1.561
20	67	3.474	0.930	-2.543
30	26	2.503	0.176	-2.327
30	27	3.143	1.711	-1.432
30	28	1.080	1.620	0.540
30	29	4.026	1.409	-2.616
30	30	1.261	2.020	0.758
50	36	1.303	1.968	0.665
50	37	4.209	3.774	-0.436
50	38	2.761	2.407	-0.354
50	39	2.325	0.947	-1.379
50	40	1.887	0.096	-1.791
	Max	4.209	3.774	1.613
	Average	2.286	1.281	-1.005
	Min	0.495	0.033	-3.613
	Std Dev	1.130	0.943	1.280



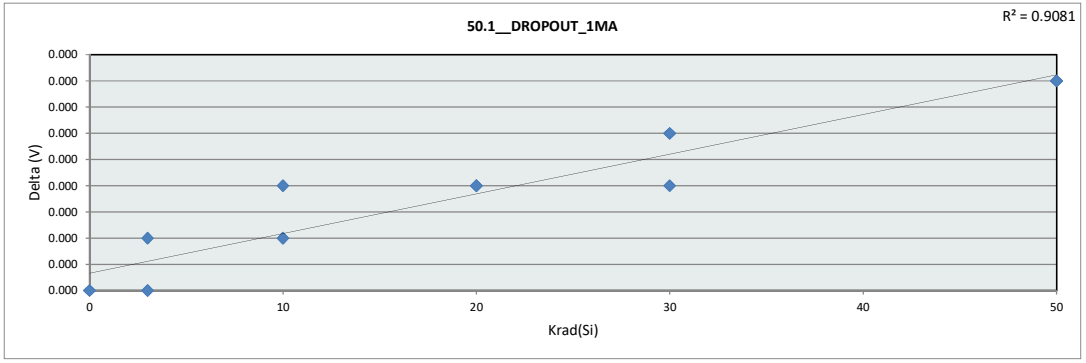
	60.6__LOAD REG					
Test Site						
Tester						
Test Number						
Max Limit	8	mV				
Min Limit		mV				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.338	0.033	0.692	0.181	0.176	0.096
Average	1.373	0.708	1.654	0.763	1.387	1.838
Max	2.607	1.416	3.270	1.007	2.020	3.774
UL	8.000	8.000	8.000	8.000	8.000	8.000



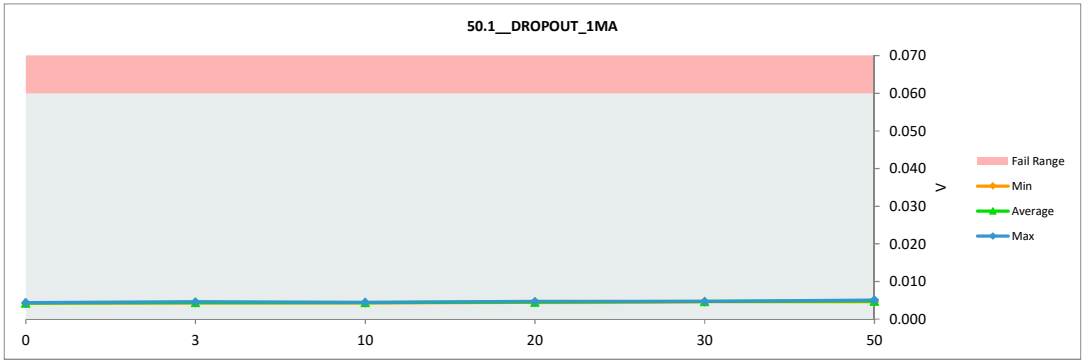
TID LDR Data (Unbiased)
TPS73801-SEP

	50.1__DROPOUT_1MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.06	0.06
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.004	0.004	0.000
0	69	0.004	0.004	0.000
0	70	0.004	0.004	0.000
3	6	0.004	0.004	0.000
3	7	0.004	0.004	0.000
3	8	0.004	0.004	0.000
3	9	0.004	0.005	0.000
3	10	0.004	0.004	0.000
10	16	0.004	0.004	0.000
10	17	0.004	0.004	0.000
10	18	0.004	0.004	0.000
10	19	0.004	0.004	0.000
10	20	0.004	0.004	0.000
20	63	0.004	0.005	0.000
20	64	0.004	0.004	0.000
20	65	0.004	0.005	0.000
20	66	0.004	0.004	0.000
20	67	0.004	0.004	0.000
30	26	0.004	0.005	0.000
30	27	0.004	0.005	0.000
30	28	0.004	0.005	0.000
30	29	0.004	0.005	0.000
30	30	0.004	0.005	0.000
50	36	0.004	0.005	0.000
50	37	0.004	0.005	0.000
50	38	0.004	0.005	0.000
50	39	0.004	0.005	0.000
50	40	0.005	0.005	0.000
	Max	0.005	0.005	0.000
	Average	0.004	0.005	0.000
	Min	0.004	0.004	0.000
	Std Dev	0.000	0.000	0.000



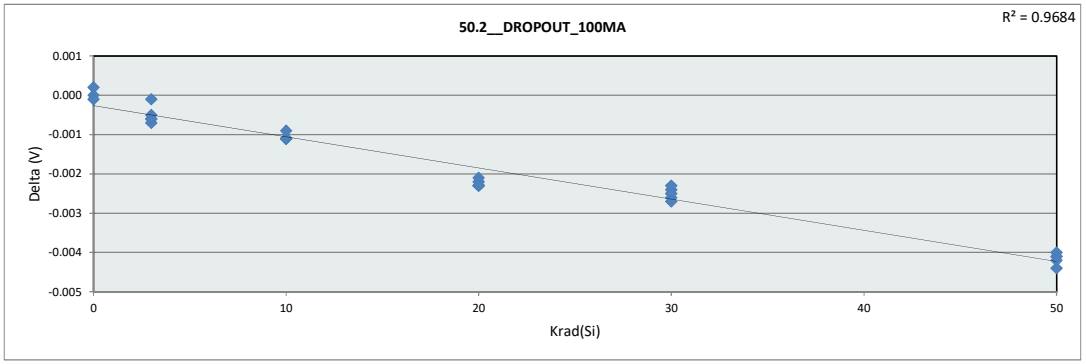
	50.1__DROPOUT_1MA					
Test Site						
Tester						
Test Number						
Max Limit	0.06	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.004	0.004	0.004	0.005	0.005	0.005
Average	0.004	0.004	0.004	0.005	0.005	0.005
Max	0.004	0.005	0.005	0.005	0.005	0.005
UL	0.060	0.060	0.060	0.060	0.060	0.060



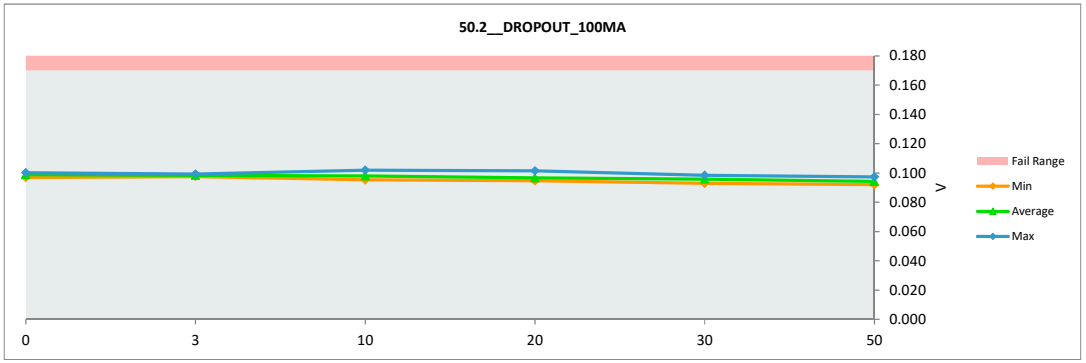
TID LDR Data (Unbiased)
TPS73801-SEP

	50.2__DROPOUT_100MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.17	0.17
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.100	0.100	0.000
0	69	0.097	0.097	0.000
0	70	0.099	0.099	0.000
3	6	0.099	0.098	-0.001
3	7	0.099	0.098	-0.001
3	8	0.098	0.098	-0.001
3	9	0.100	0.099	-0.001
3	10	0.098	0.098	0.000
10	16	0.103	0.102	-0.001
10	17	0.096	0.095	-0.001
10	18	0.101	0.099	-0.001
10	19	0.097	0.096	-0.001
10	20	0.098	0.097	-0.001
20	63	0.097	0.095	-0.002
20	64	0.097	0.095	-0.002
20	65	0.104	0.101	-0.002
20	66	0.097	0.095	-0.002
20	67	0.100	0.097	-0.002
30	26	0.099	0.097	-0.002
30	27	0.098	0.096	-0.002
30	28	0.095	0.093	-0.003
30	29	0.098	0.095	-0.003
30	30	0.101	0.098	-0.003
50	36	0.096	0.092	-0.004
50	37	0.098	0.094	-0.004
50	38	0.098	0.094	-0.004
50	39	0.097	0.093	-0.004
50	40	0.101	0.097	-0.004
Max		0.104	0.102	0.000
Average		0.099	0.097	-0.002
Min		0.095	0.092	-0.004
Std Dev		0.002	0.003	0.001



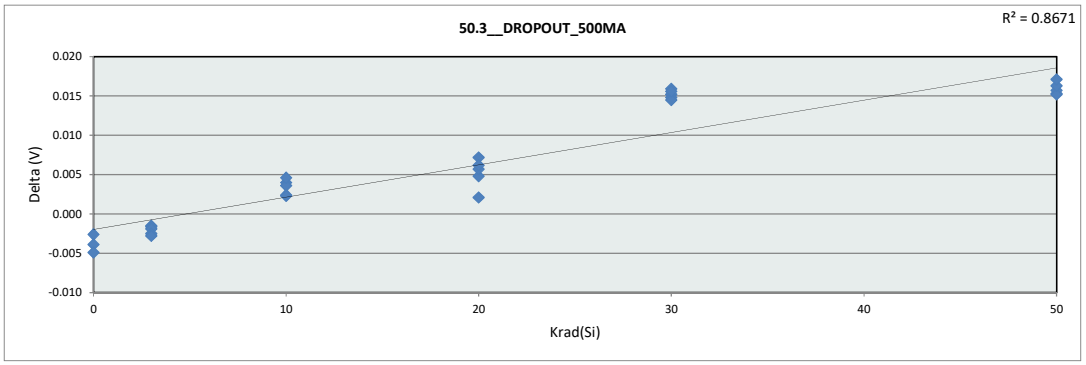
	50.2__DROPOUT_100MA					
Test Site						
Tester						
Test Number						
Max Limit	0.17	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.097	0.098	0.095	0.095	0.093	0.092
Average	0.099	0.098	0.098	0.097	0.096	0.094
Max	0.100	0.099	0.102	0.102	0.098	0.097
UL	0.170	0.170	0.170	0.170	0.170	0.170



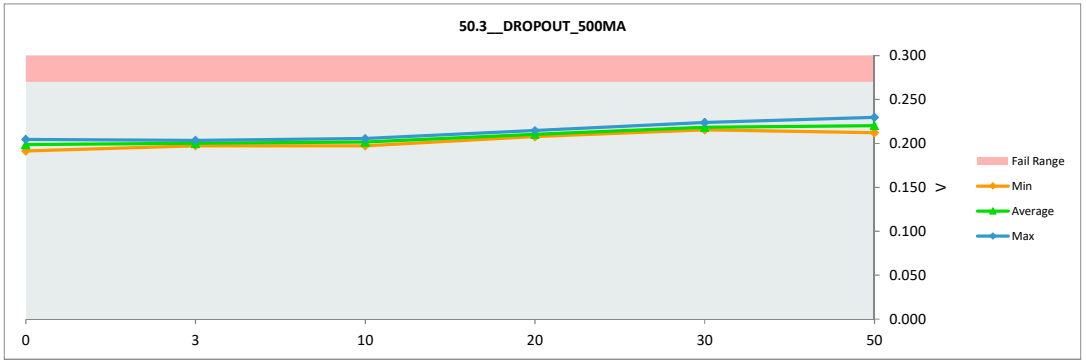
TID LDR Data (Unbiased)
TPS73801-SEP

	50.3__DROPOUT_500MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.27	0.27
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.207	0.205	-0.003
0	69	0.196	0.192	-0.004
0	70	0.205	0.200	-0.005
3	6	0.199	0.197	-0.001
3	7	0.205	0.204	-0.002
3	8	0.202	0.200	-0.002
3	9	0.203	0.201	-0.002
3	10	0.201	0.198	-0.003
10	16	0.200	0.204	0.004
10	17	0.195	0.197	0.002
10	18	0.198	0.200	0.002
10	19	0.197	0.200	0.004
10	20	0.201	0.206	0.005
20	63	0.206	0.209	0.002
20	64	0.205	0.210	0.005
20	65	0.209	0.215	0.006
20	66	0.200	0.208	0.007
20	67	0.206	0.212	0.006
30	26	0.204	0.219	0.015
30	27	0.201	0.215	0.015
30	28	0.202	0.218	0.016
30	29	0.201	0.216	0.015
30	30	0.208	0.224	0.016
50	36	0.208	0.223	0.015
50	37	0.197	0.212	0.016
50	38	0.199	0.214	0.015
50	39	0.206	0.222	0.016
50	40	0.213	0.230	0.017
	Max	0.213	0.230	0.017
	Average	0.203	0.209	0.006
	Min	0.195	0.192	-0.005
	Std Dev	0.004	0.010	0.008



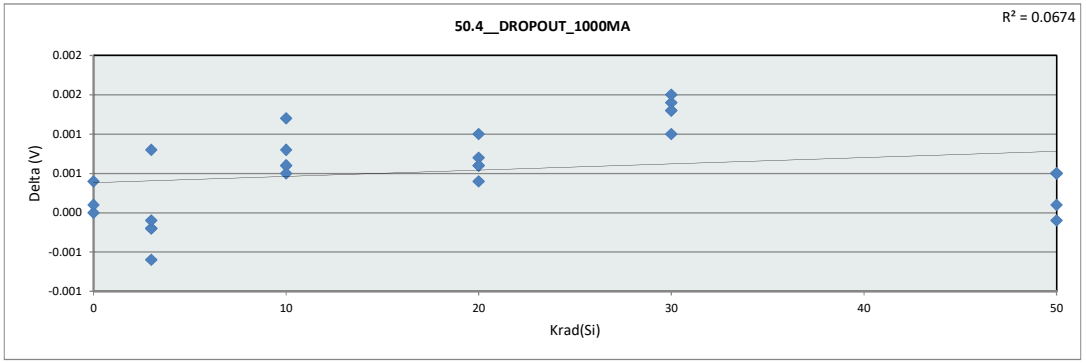
	50.3__DROPOUT_500MA					
Test Site						
Tester						
Test Number						
Max Limit	0.27	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.192	0.197	0.197	0.208	0.216	0.212
Average	0.199	0.200	0.202	0.211	0.218	0.220
Max	0.205	0.204	0.206	0.215	0.224	0.230
UL	0.270	0.270	0.270	0.270	0.270	0.270



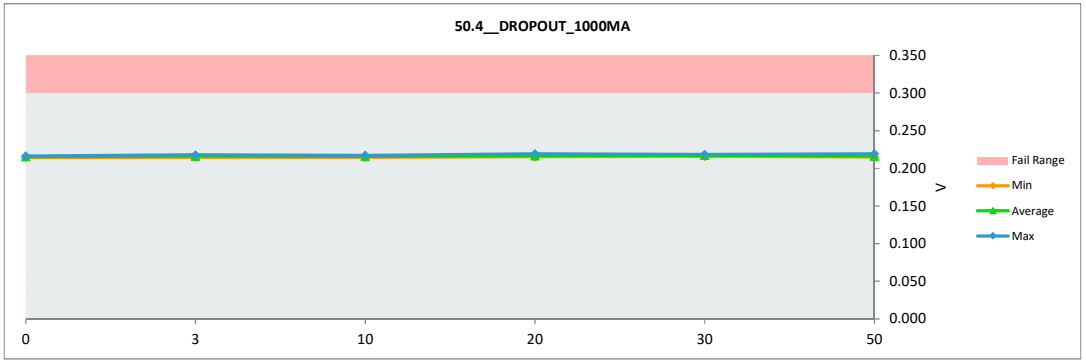
TID LDR Data (Unbiased)
TPS73801-SEP

	50.4__DROPOUT_1000MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.3	0.3
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.216	0.216	0.000
0	69	0.214	0.214	0.000
0	70	0.216	0.216	0.000
3	6	0.215	0.215	-0.001
3	7	0.216	0.216	0.000
3	8	0.217	0.216	0.000
3	9	0.218	0.218	0.000
3	10	0.215	0.216	0.001
10	16	0.216	0.217	0.001
10	17	0.214	0.215	0.001
10	18	0.217	0.217	0.001
10	19	0.214	0.215	0.000
10	20	0.215	0.217	0.001
20	63	0.215	0.216	0.000
20	64	0.215	0.215	0.001
20	65	0.218	0.219	0.001
20	66	0.215	0.216	0.001
20	67	0.216	0.217	0.001
30	26	0.217	0.218	0.001
30	27	0.216	0.217	0.001
30	28	0.215	0.216	0.001
30	29	0.216	0.217	0.001
30	30	0.217	0.218	0.001
50	36	0.215	0.215	0.000
50	37	0.215	0.215	0.001
50	38	0.217	0.217	0.000
50	39	0.215	0.215	0.000
50	40	0.219	0.219	0.001
Max		0.219	0.219	0.001
Average		0.216	0.216	0.001
Min		0.214	0.214	-0.001
Std Dev		0.001	0.001	0.001



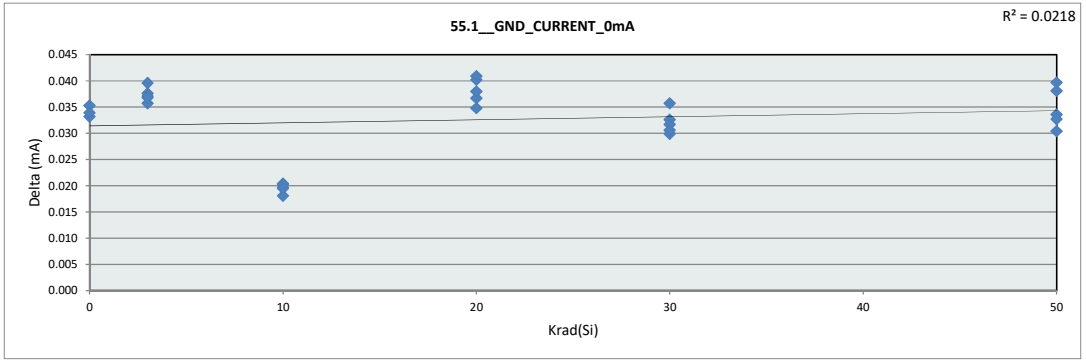
	50.4__DROPOUT_1000MA					
Test Site						
Tester						
Test Number						
Max Limit	0.3	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.214	0.215	0.215	0.215	0.216	0.215
Average	0.215	0.216	0.216	0.217	0.217	0.216
Max	0.216	0.218	0.217	0.219	0.218	0.219
UL	0.300	0.300	0.300	0.300	0.300	0.300



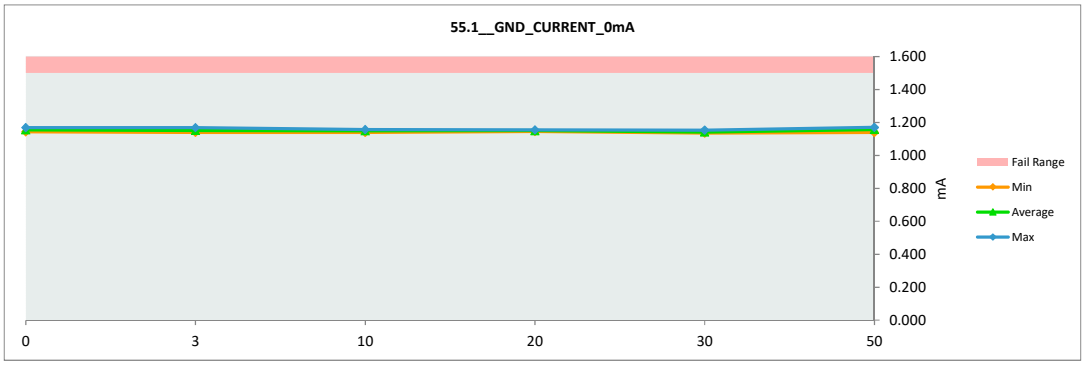
TID LDR Data (Unbiased)
TPS73801-SEP

	55.1__GND_CURRENT_0mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	1.5	1.5
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.110	1.144	0.033
0	69	1.135	1.170	0.035
0	70	1.118	1.152	0.034
3	6	1.132	1.169	0.038
3	7	1.104	1.140	0.036
3	8	1.106	1.143	0.037
3	9	1.115	1.151	0.037
3	10	1.114	1.153	0.040
10	16	1.129	1.147	0.018
10	17	1.137	1.157	0.020
10	18	1.120	1.140	0.020
10	19	1.138	1.158	0.020
10	20	1.123	1.143	0.020
20	63	1.118	1.154	0.037
20	64	1.114	1.152	0.038
20	65	1.110	1.145	0.035
20	66	1.115	1.156	0.040
20	67	1.109	1.149	0.041
30	26	1.108	1.140	0.033
30	27	1.105	1.137	0.032
30	28	1.114	1.144	0.030
30	29	1.118	1.154	0.036
30	30	1.104	1.135	0.031
50	36	1.123	1.162	0.040
50	37	1.136	1.170	0.034
50	38	1.127	1.157	0.030
50	39	1.107	1.139	0.033
50	40	1.120	1.158	0.038
Max		1.138	1.170	0.041
Average		1.118	1.151	0.033
Min		1.104	1.135	0.018
Std Dev		0.011	0.010	0.007



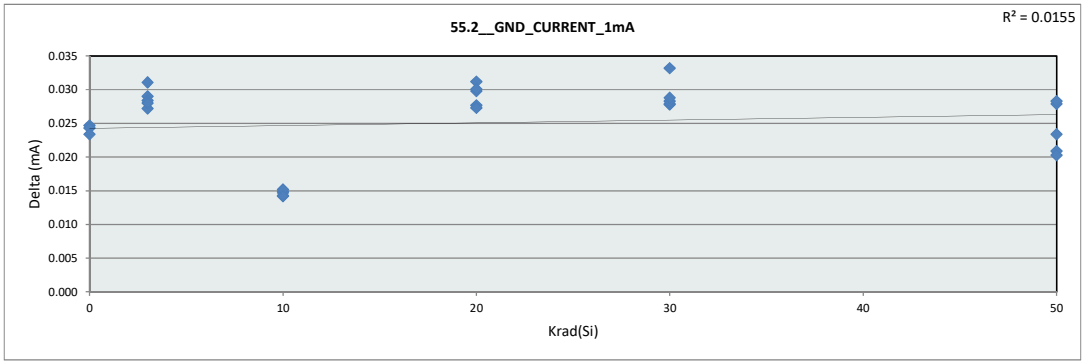
	55.1__GND_CURRENT_0mA					
Test Site						
Tester						
Test Number						
Max Limit	1.5	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.144	1.140	1.140	1.145	1.135	1.139
Average	1.155	1.151	1.149	1.151	1.142	1.157
Max	1.170	1.170	1.158	1.156	1.154	1.170
UL	1.500	1.500	1.500	1.500	1.500	1.500



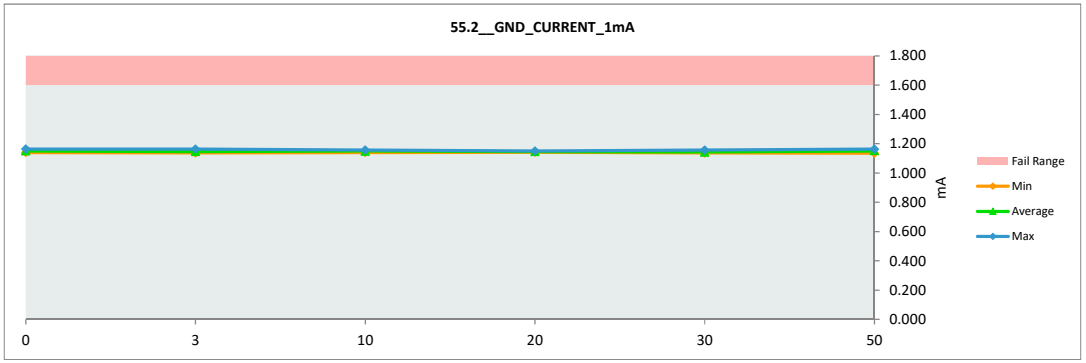
TID LDR Data (Unbiased)
TPS73801-SEP

	55.2__GND_CURRENT_1mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	1.6	1.6
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.115	1.140	0.025
0	69	1.140	1.164	0.024
0	70	1.123	1.146	0.023
3	6	1.137	1.164	0.027
3	7	1.107	1.136	0.029
3	8	1.109	1.138	0.028
3	9	1.119	1.147	0.028
3	10	1.119	1.150	0.031
10	16	1.133	1.148	0.015
10	17	1.143	1.157	0.014
10	18	1.125	1.140	0.015
10	19	1.142	1.157	0.015
10	20	1.128	1.142	0.014
20	63	1.123	1.150	0.028
20	64	1.118	1.147	0.030
20	65	1.114	1.142	0.027
20	66	1.119	1.150	0.031
20	67	1.114	1.144	0.030
30	26	1.113	1.141	0.028
30	27	1.109	1.137	0.028
30	28	1.117	1.145	0.028
30	29	1.122	1.156	0.033
30	30	1.108	1.137	0.029
50	36	1.128	1.156	0.028
50	37	1.142	1.163	0.021
50	38	1.132	1.153	0.020
50	39	1.111	1.134	0.023
50	40	1.123	1.152	0.028
	Max	1.143	1.164	0.033
	Average	1.123	1.148	0.025
	Min	1.107	1.134	0.014
	Std Dev	0.011	0.009	0.006



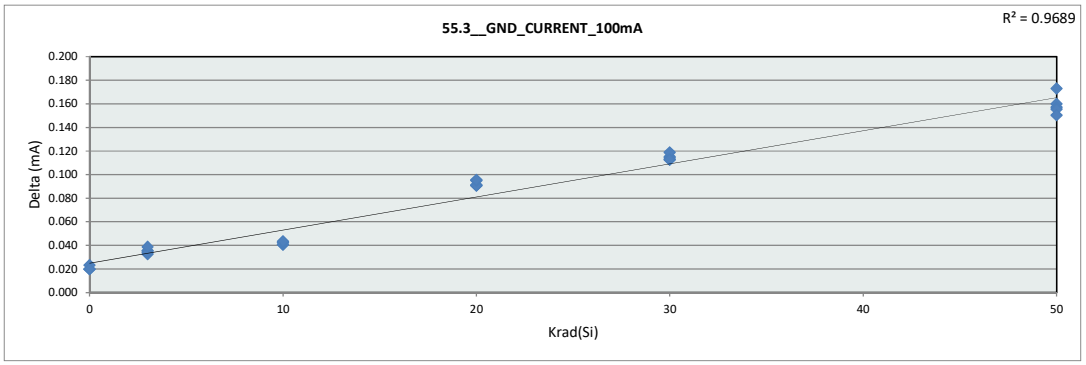
	55.2__GND_CURRENT_1mA					
Test Site						
Tester						
Test Number						
Max Limit	1.6	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.140	1.136	1.140	1.142	1.137	1.134
Average	1.150	1.147	1.149	1.147	1.143	1.151
Max	1.164	1.164	1.157	1.150	1.156	1.163
UL	1.600	1.600	1.600	1.600	1.600	1.600



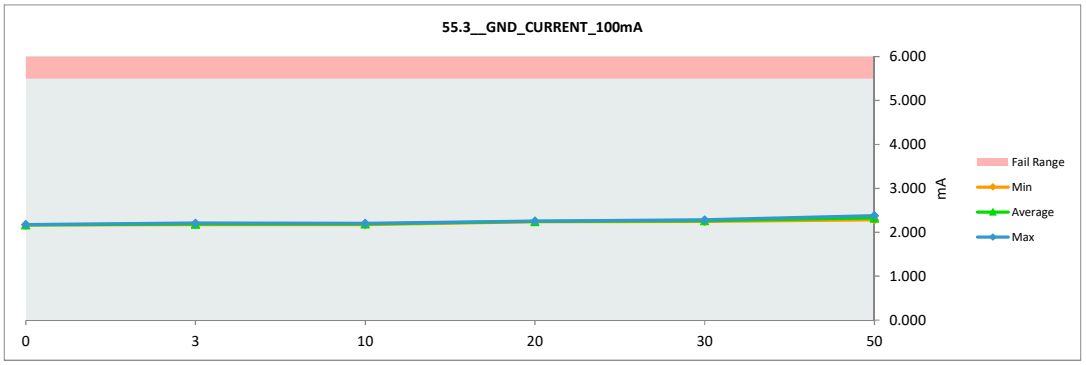
TID LDR Data (Unbiased)
TPS73801-SEP

	55.3__GND_CURRENT_100mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	5.5	5.5
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	2.146	2.165	0.020
0	69	2.141	2.165	0.023
0	70	2.156	2.176	0.020
3	6	2.156	2.188	0.033
3	7	2.140	2.175	0.035
3	8	2.142	2.178	0.036
3	9	2.174	2.208	0.034
3	10	2.142	2.181	0.039
10	16	2.134	2.175	0.041
10	17	2.152	2.193	0.041
10	18	2.136	2.179	0.043
10	19	2.161	2.203	0.043
10	20	2.161	2.204	0.043
20	63	2.165	2.256	0.091
20	64	2.153	2.244	0.091
20	65	2.151	2.242	0.091
20	66	2.155	2.251	0.095
20	67	2.148	2.244	0.095
30	26	2.153	2.268	0.115
30	27	2.134	2.248	0.114
30	28	2.153	2.266	0.113
30	29	2.162	2.281	0.119
30	30	2.148	2.261	0.113
50	36	2.172	2.332	0.160
50	37	2.159	2.316	0.157
50	38	2.168	2.324	0.155
50	39	2.137	2.287	0.150
50	40	2.205	2.378	0.173
	Max	2.205	2.378	0.173
	Average	2.154	2.235	0.082
	Min	2.134	2.165	0.020
	Std Dev	0.015	0.058	0.050



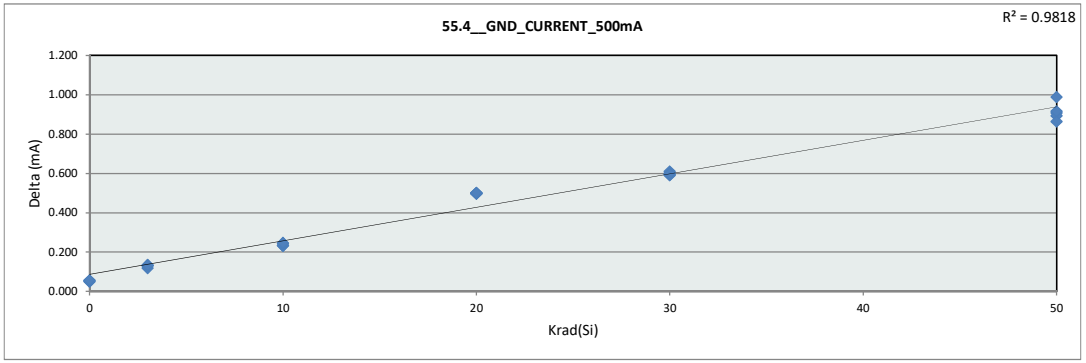
	55.3__GND_CURRENT_100mA					
Test Site						
Tester						
Test Number						
Max Limit	5.5	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	2.165	2.175	2.175	2.242	2.248	2.287
Average	2.169	2.186	2.191	2.247	2.265	2.327
Max	2.176	2.208	2.204	2.256	2.281	2.379
UL	5.500	5.500	5.500	5.500	5.500	5.500



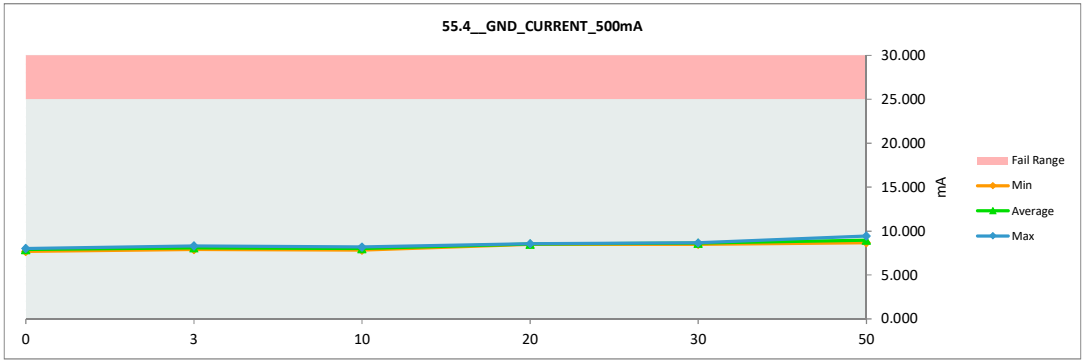
TID LDR Data (Unbiased)
TPS73801-SEP

	55.4__GND_CURRENT_500mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	25	25
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	7.946	7.996	0.049
0	69	7.633	7.686	0.053
0	70	7.958	8.015	0.057
3	6	7.785	7.903	0.118
3	7	7.953	8.085	0.133
3	8	7.990	8.122	0.131
3	9	8.179	8.308	0.129
3	10	7.860	7.994	0.134
10	16	7.606	7.839	0.233
10	17	7.728	7.960	0.232
10	18	7.732	7.966	0.234
10	19	7.795	8.038	0.243
10	20	7.936	8.182	0.246
20	63	8.067	8.564	0.498
20	64	7.997	8.493	0.496
20	65	8.023	8.522	0.500
20	66	7.989	8.491	0.501
20	67	7.974	8.475	0.501
30	26	8.064	8.663	0.600
30	27	7.890	8.480	0.590
30	28	8.021	8.615	0.593
30	29	8.059	8.668	0.609
30	30	8.022	8.620	0.598
50	36	8.118	9.026	0.908
50	37	7.782	8.674	0.892
50	38	8.007	8.924	0.917
50	39	7.915	8.778	0.863
50	40	8.461	9.450	0.989
Max		8.461	9.450	0.989
Average		7.946	8.376	0.430
Min		7.606	7.686	0.049
Std Dev		0.173	0.411	0.299



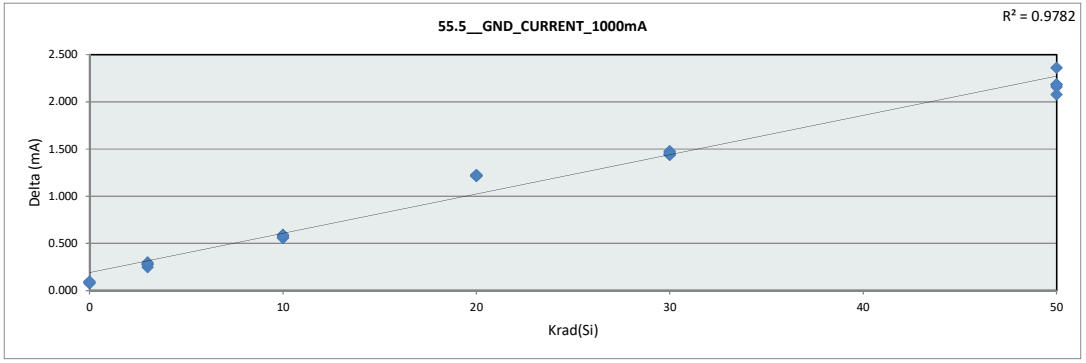
	55.4__GND_CURRENT_500mA					
Test Site						
Tester						
Test Number						
Max Limit	25	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	7.686	7.903	7.839	8.475	8.480	8.674
Average	7.899	8.082	7.997	8.509	8.609	8.970
Max	8.015	8.308	8.182	8.564	8.668	9.450
UL	25.000	25.000	25.000	25.000	25.000	25.000



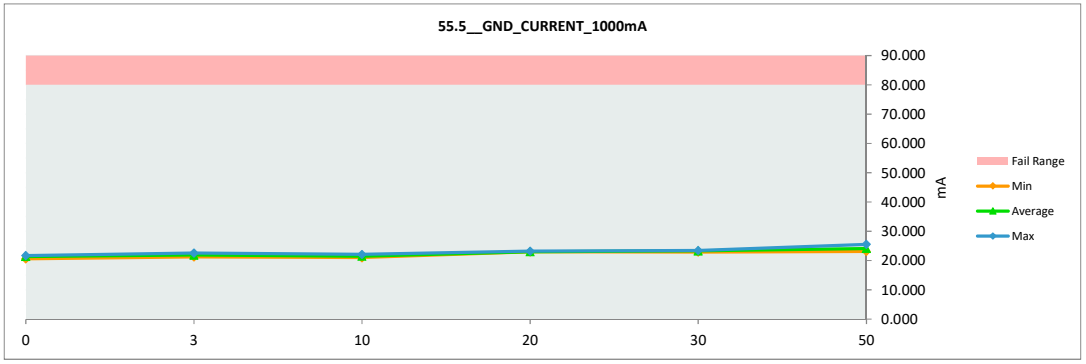
TID LDR Data (Unbiased)
TPS73801-SEP

	55.5__GND_CURRENT_1000mA	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	80	80
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	21.636	21.714	0.077
0	69	20.544	20.630	0.086
0	70	21.641	21.737	0.096
3	6	21.016	21.265	0.249
3	7	21.670	21.953	0.283
3	8	21.811	22.094	0.283
3	9	22.307	22.583	0.276
3	10	21.325	21.621	0.297
10	16	20.462	21.020	0.558
10	17	20.854	21.417	0.564
10	18	20.887	21.458	0.571
10	19	21.037	21.626	0.589
10	20	21.536	22.127	0.590
20	63	21.997	23.211	1.214
20	64	21.814	23.028	1.214
20	65	21.876	23.101	1.225
20	66	21.758	22.979	1.221
20	67	21.721	22.941	1.220
30	26	22.001	23.470	1.469
30	27	21.458	22.898	1.440
30	28	21.910	23.347	1.438
30	29	21.974	23.452	1.478
30	30	21.891	23.344	1.453
50	36	22.220	24.405	2.184
50	37	20.989	23.148	2.160
50	38	21.725	23.908	2.184
50	39	21.583	23.661	2.078
50	40	23.202	25.561	2.360
Max		23.202	25.561	2.360
Average		21.602	22.632	1.031
Min		20.462	20.630	0.077
Std Dev		0.575	1.124	0.731



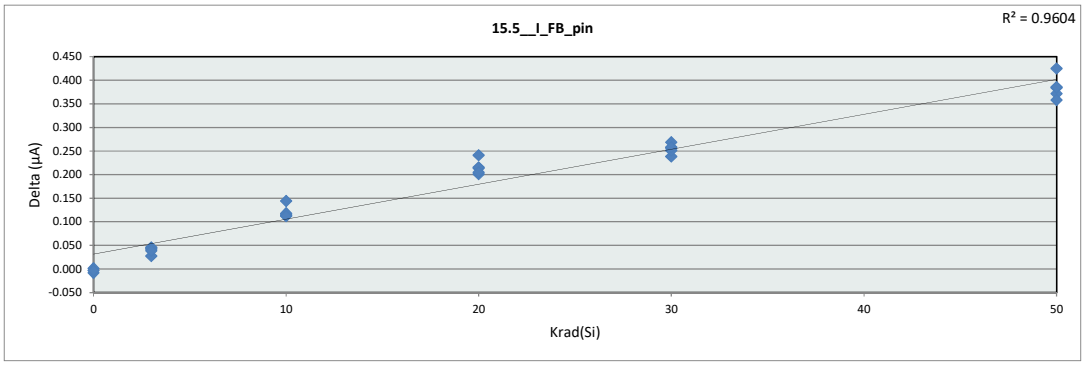
	55.5__GND_CURRENT_1000mA					
Test Site						
Tester						
Test Number						
Max Limit	80	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	20.630	21.265	21.020	22.941	22.898	23.148
Average	21.360	21.903	21.530	23.052	23.302	24.137
Max	21.737	22.583	22.127	23.211	23.470	25.561
UL	80.000	80.000	80.000	80.000	80.000	80.000



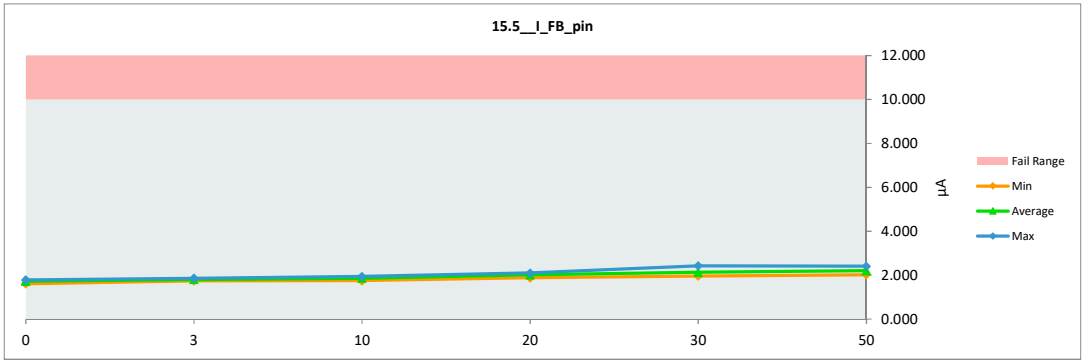
TID LDR Data (Unbiased)
TPS73801-SEP

	15.5__I_FB_pin	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	10	10
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.794	1.786	-0.008
0	69	1.607	1.608	0.001
0	70	1.792	1.789	-0.003
3	6	1.774	1.818	0.044
3	7	1.790	1.817	0.027
3	8	1.716	1.762	0.046
3	9	1.697	1.738	0.042
3	10	1.825	1.864	0.039
10	16	1.659	1.776	0.117
10	17	1.811	1.924	0.113
10	18	1.631	1.749	0.118
10	19	1.802	1.947	0.144
10	20	1.792	1.905	0.113
20	63	1.862	2.103	0.241
20	64	1.857	2.071	0.214
20	65	1.683	1.885	0.201
20	66	1.838	2.053	0.215
20	67	1.761	1.966	0.205
30	26	1.726	1.964	0.238
30	27	1.953	2.209	0.257
30	28	2.164	2.432	0.269
30	29	1.765	2.016	0.251
30	30	1.797	2.055	0.258
50	36	1.984	2.409	0.425
50	37	1.927	2.299	0.372
50	38	1.661	2.019	0.358
50	39	1.823	2.207	0.384
50	40	1.726	2.112	0.385
Max		2.164	2.432	0.425
Average		1.793	1.974	0.181
Min		1.607	1.608	-0.008
Std Dev		0.116	0.206	0.131



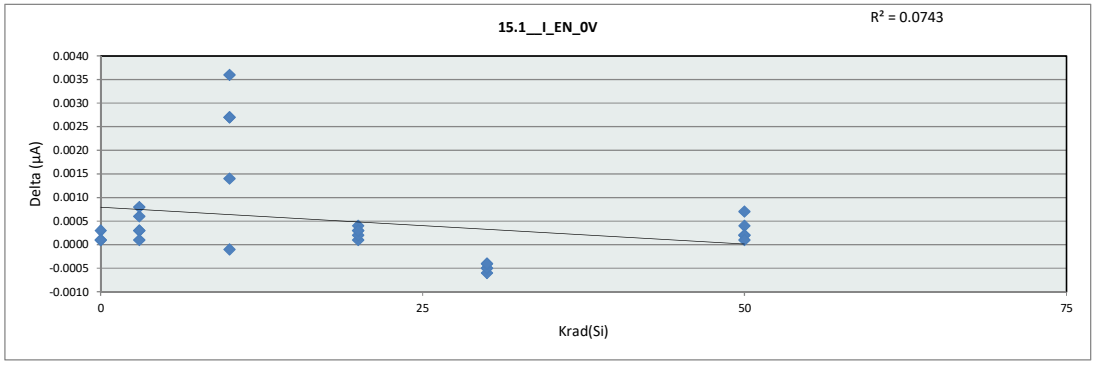
	15.5__I_FB_pin					
Test Site						
Tester						
Test Number						
Max Limit	10	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.608	1.739	1.749	1.885	1.964	2.019
Average	1.727	1.800	1.860	2.016	2.135	2.209
Max	1.789	1.864	1.947	2.103	2.433	2.409
UL	10.000	10.000	10.000	10.000	10.000	10.000



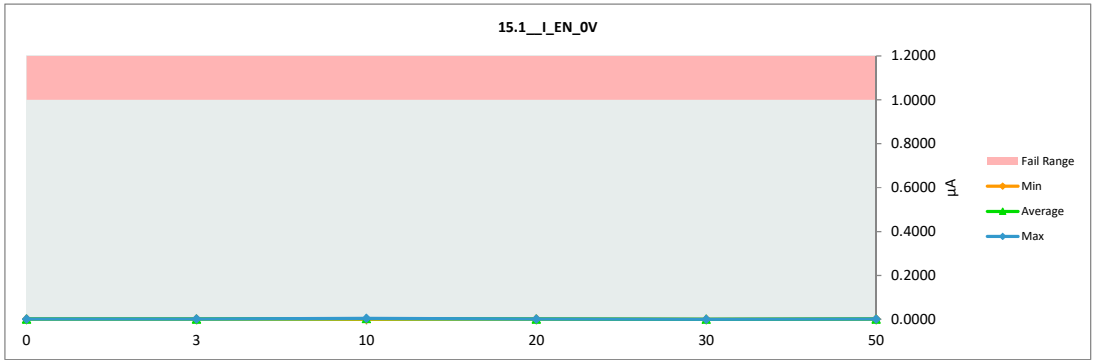
TID LDR Data (Unbiased)
TPS73801-SEP

	15.1__I_EN_0V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	1	1
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.0011	0.0012	0.0001
0	69	0.0009	0.0012	0.0003
0	70	0.0012	0.0013	0.0001
3	6	0.0010	0.0013	0.0003
3	7	0.0011	0.0014	0.0003
3	8	0.0007	0.0013	0.0006
3	9	0.0008	0.0016	0.0008
3	10	0.0011	0.0012	0.0001
10	16	0.0011	0.0025	0.0014
10	17	0.0011	0.0047	0.0036
10	18	0.0007	0.0006	-0.0001
10	19	0.0010	0.0037	0.0027
10	20	0.0008	0.0035	0.0027
20	63	0.0011	0.0012	0.0001
20	64	0.0011	0.0013	0.0002
20	65	0.0009	0.0013	0.0004
20	66	0.0009	0.0012	0.0003
20	67	0.0010	0.0013	0.0003
30	26	0.0008	0.0002	-0.0006
30	27	0.0008	0.0003	-0.0005
30	28	0.0008	0.0003	-0.0005
30	29	0.0008	0.0004	-0.0004
30	30	0.0009	0.0005	-0.0004
50	36	0.0003	0.0010	0.0007
50	37	0.0007	0.0011	0.0004
50	38	0.0008	0.0010	0.0002
50	39	0.0009	0.0011	0.0002
50	40	0.0009	0.0010	0.0001
	Max	0.0012	0.0047	0.0036
	Average	0.0009	0.0014	0.0005
	Min	0.0003	0.0002	-0.0006
	Std Dev	0.0002	0.0010	0.0010



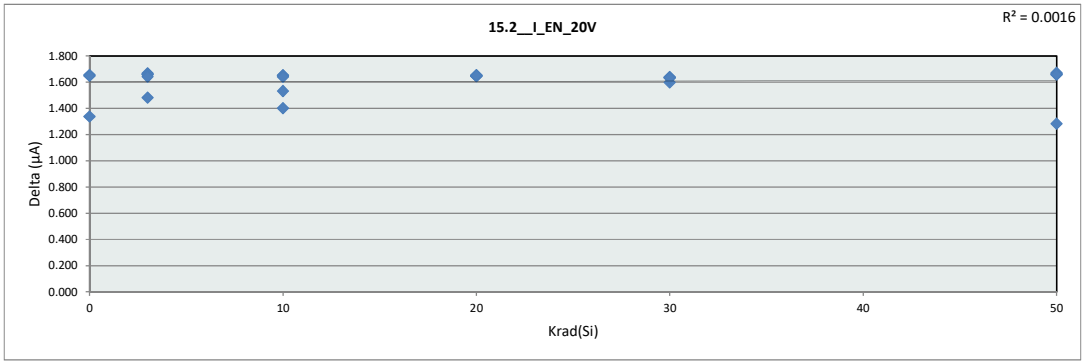
	15.1__I_EN_0V					
Test Site						
Tester						
Test Number						
Max Limit	1	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.0012	0.0012	0.0006	0.0012	0.0002	0.0010
Average	0.0012	0.0014	0.0030	0.0013	0.0003	0.0010
Max	0.0013	0.0016	0.0047	0.0013	0.0005	0.0011
UL	1.0000	1.0000	1.0000	1.0000	1.0000	1.0000



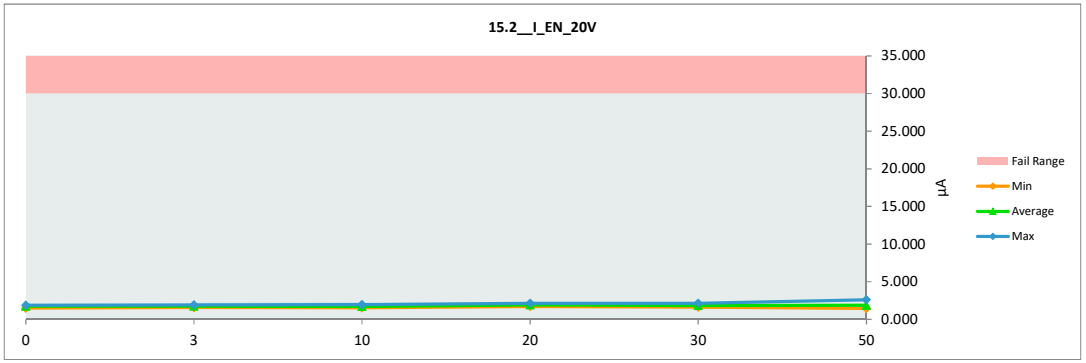
TID LDR Data (Unbiased)
TPS73801-SEP

	15.2__I_EN_20V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	30	30
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.218	1.874	1.656
0	69	0.158	1.496	1.339
0	70	0.173	1.822	1.648
3	6	0.255	1.923	1.668
3	7	0.218	1.877	1.659
3	8	0.021	1.680	1.660
3	9	0.088	1.571	1.482
3	10	0.196	1.839	1.643
10	16	0.061	1.594	1.533
10	17	0.172	1.825	1.653
10	18	0.123	1.526	1.403
10	19	0.289	1.940	1.652
10	20	0.088	1.729	1.641
20	63	0.499	2.153	1.654
20	64	0.339	1.986	1.647
20	65	0.077	1.722	1.646
20	66	0.205	1.856	1.651
20	67	0.176	1.825	1.650
30	26	0.075	1.712	1.637
30	27	0.018	1.617	1.599
30	28	0.512	2.151	1.639
30	29	0.197	1.831	1.634
30	30	0.226	1.861	1.635
50	36	0.924	2.595	1.671
50	37	0.056	1.714	1.657
50	38	0.189	1.472	1.284
50	39	0.197	1.861	1.664
50	40	0.065	1.726	1.661
	Max	0.924	2.595	1.671
	Average	0.208	1.814	1.606
	Min	0.018	1.472	1.284
	Std Dev	0.186	0.229	0.103



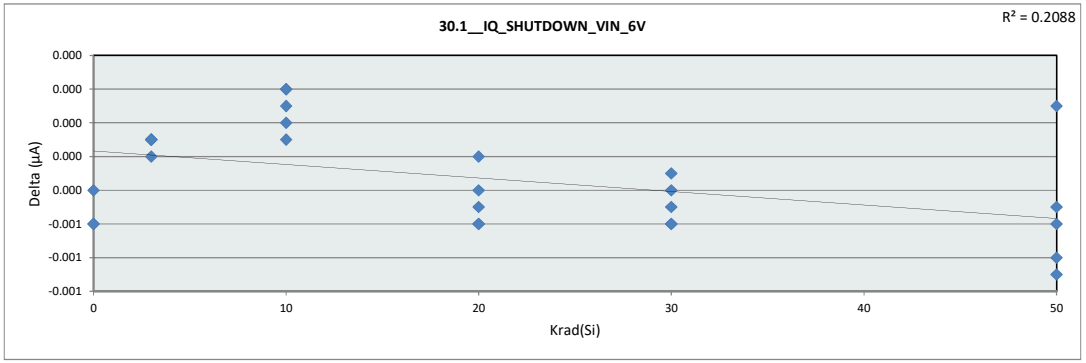
	15.2__I_EN_20V					
Test Site						
Tester						
Test Number						
Max Limit	30	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.496	1.571	1.526	1.723	1.617	1.472
Average	1.731	1.778	1.723	1.909	1.834	1.874
Max	1.874	1.923	1.940	2.153	2.151	2.596
UL	30.000	30.000	30.000	30.000	30.000	30.000



TID LDR Data (Unbiased)
TPS73801-SEP

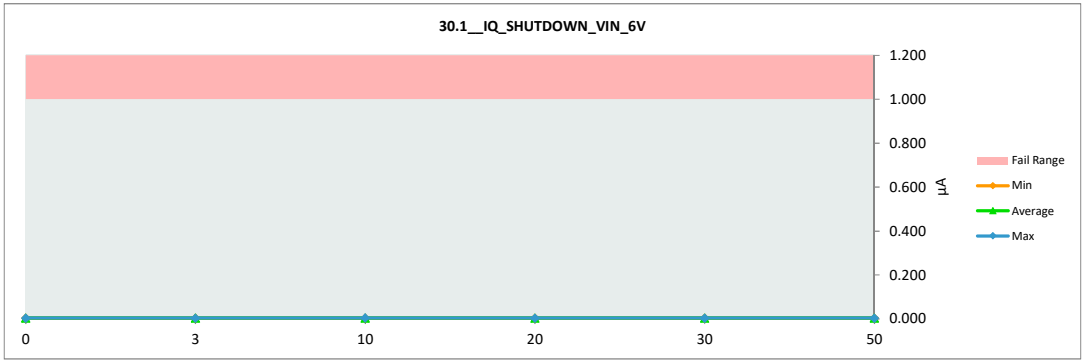
	30.1__IQ_SHUTDOWN_VIN_6V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	1	1
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.004	0.004	-0.001
0	69	0.004	0.004	0.000
0	70	0.004	0.004	-0.001
3	6	0.004	0.004	0.000
3	7	0.004	0.004	0.000
3	8	0.004	0.004	0.000
3	9	0.004	0.004	0.000
3	10	0.004	0.004	0.000
10	16	0.004	0.004	0.000
10	17	0.004	0.004	0.000
10	18	0.004	0.004	0.000
10	19	0.004	0.004	0.000
10	20	0.004	0.004	0.000
20	63	0.004	0.004	0.000
20	64	0.004	0.004	0.000
20	65	0.004	0.004	-0.001
20	66	0.004	0.004	-0.001
20	67	0.004	0.004	-0.001
30	26	0.004	0.004	0.000
30	27	0.004	0.004	-0.001
30	28	0.004	0.004	-0.001
30	29	0.004	0.004	-0.001
30	30	0.004	0.004	0.000
50	36	0.005	0.004	-0.001
50	37	0.004	0.004	-0.001
50	38	0.005	0.004	-0.001
50	39	0.004	0.004	-0.001
50	40	0.004	0.004	0.000
	Max	0.005	0.004	0.000
	Average	0.004	0.004	0.000
	Min	0.004	0.004	-0.001
	Std Dev	0.000	0.000	0.000



	30.1__IQ_SHUTDOWN_VIN_6V	
Test Site		
Tester		
Test Number		
Max Limit	1	µA
Min Limit		µA

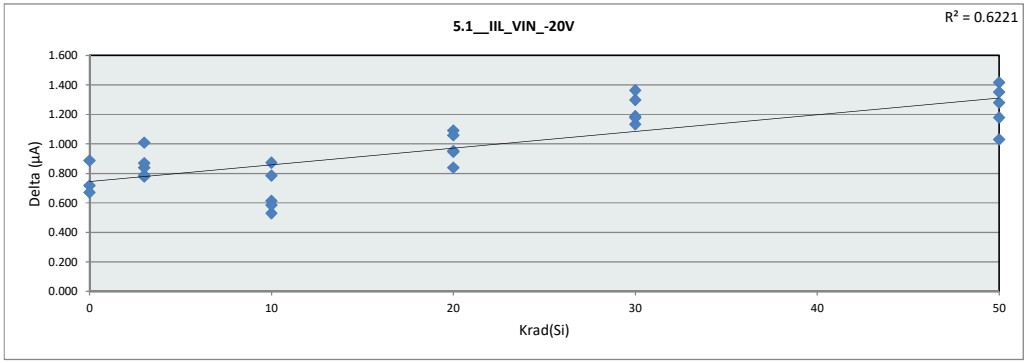
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.004	0.004	0.004	0.004	0.004	0.004
Average	0.004	0.004	0.004	0.004	0.004	0.004
Max	0.004	0.004	0.004	0.004	0.004	0.004
UL	1.000	1.000	1.000	1.000	1.000	1.000



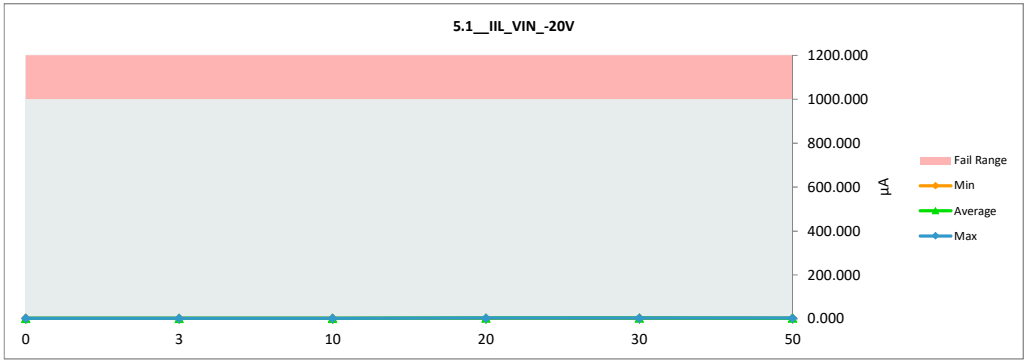
TID LDR Data (Unbiased)
TPS73801-SEP

	5.1__IIL_VIN_-20V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	1000	1000
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	2.185	2.903	0.718
0	69	2.152	3.039	0.888
0	70	2.208	2.879	0.671
3	6	2.095	3.103	1.008
3	7	2.088	2.927	0.839
3	8	2.090	2.877	0.788
3	9	2.046	2.916	0.870
3	10	2.158	2.938	0.779
10	16	2.184	2.714	0.530
10	17	2.174	2.960	0.786
10	18	2.256	2.870	0.614
10	19	2.249	3.121	0.873
10	20	2.297	2.881	0.585
20	63	2.255	3.346	1.091
20	64	2.287	3.346	1.059
20	65	2.368	3.206	0.838
20	66	2.411	3.358	0.947
20	67	2.262	3.214	0.952
30	26	2.158	3.521	1.363
30	27	2.345	3.478	1.133
30	28	2.234	3.422	1.188
30	29	2.311	3.609	1.298
30	30	2.316	3.494	1.177
50	36	2.348	3.764	1.416
50	37	2.373	3.653	1.280
50	38	2.408	3.760	1.352
50	39	2.506	3.537	1.031
50	40	2.262	3.440	1.178
Max		2.506	3.764	1.416
Average		2.251	3.224	0.973
Min		2.046	2.714	0.530
Std Dev		0.112	0.311	0.249



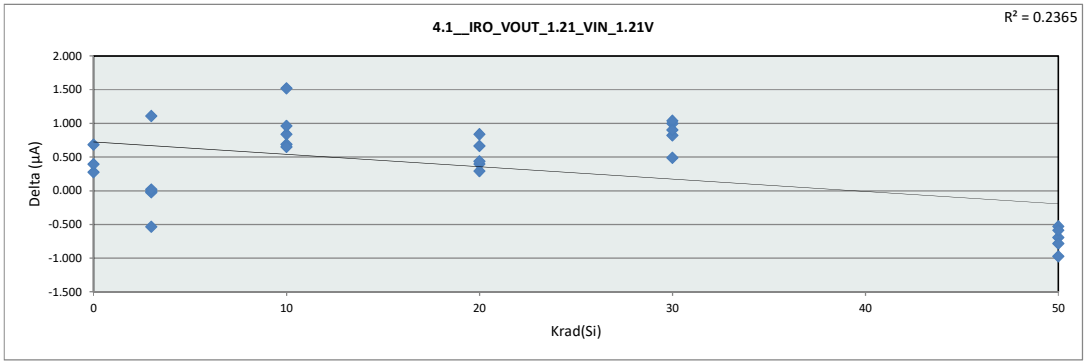
	5.1__IIL_VIN_-20V					
Test Site						
Tester						
Test Number						
Max Limit	1000	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	2.879	2.877	2.714	3.206	3.422	3.440
Average	2.940	2.952	2.909	3.294	3.505	3.631
Max	3.039	3.103	3.121	3.358	3.609	3.764
UL	1000.000	1000.000	1000.000	1000.000	1000.000	1000.000



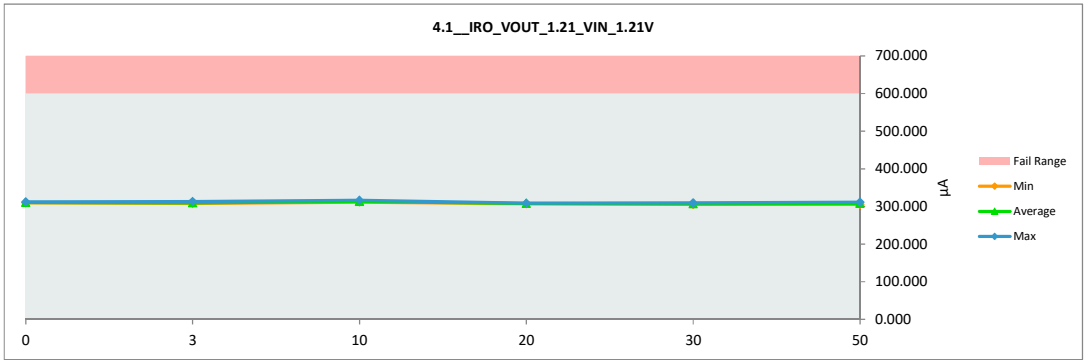
TID LDR Data (Unbiased)
TPS73801-SEP

	4.1__IRO_VOUT_1.21_VIN_1.21V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	600	600
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	309.297	309.573	0.275
0	69	311.463	311.858	0.395
0	70	309.543	310.229	0.686
3	6	313.828	313.294	-0.534
3	7	308.006	307.999	-0.007
3	8	307.667	307.643	-0.023
3	9	310.986	311.004	0.018
3	10	308.776	309.886	1.110
10	16	315.489	316.330	0.841
10	17	311.520	312.207	0.688
10	18	310.716	311.680	0.963
10	19	311.706	312.356	0.651
10	20	312.140	313.659	1.520
20	63	306.815	307.108	0.293
20	64	308.211	308.877	0.666
20	65	307.001	307.840	0.838
20	66	308.517	308.914	0.397
20	67	308.480	308.918	0.438
30	26	305.153	305.974	0.822
30	27	306.372	307.371	0.998
30	28	304.482	304.971	0.489
30	29	308.218	309.256	1.038
30	30	307.288	308.190	0.901
50	36	306.806	305.832	-0.974
50	37	311.026	310.498	-0.528
50	38	311.953	311.259	-0.694
50	39	305.966	305.183	-0.783
50	40	309.272	308.686	-0.586
Max		315.489	316.330	1.520
Average		309.168	309.521	0.353
Min		304.482	304.971	-0.974
Std Dev		2.630	2.711	0.656



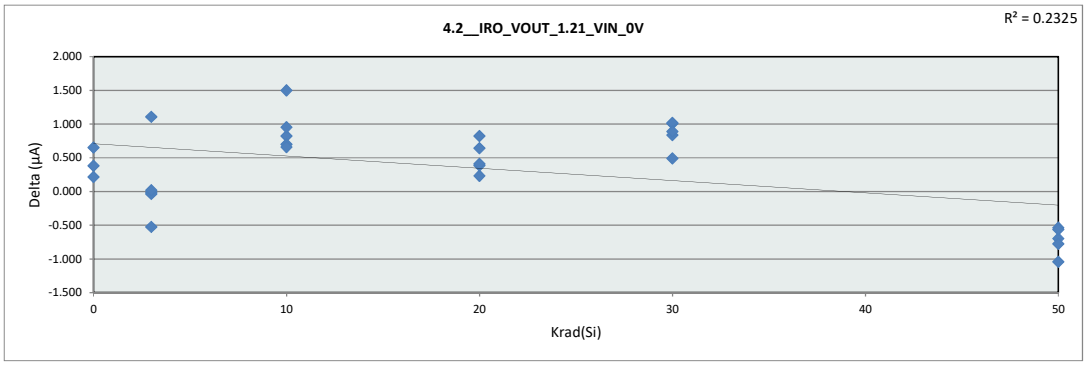
	4.1__IRO_VOUT_1.21_VIN_1.21V					
Test Site						
Tester						
Test Number						
Max Limit	600	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	309.573	307.643	311.680	307.108	304.971	305.183
Average	310.553	309.965	313.247	308.331	307.152	308.292
Max	311.858	313.294	316.330	308.919	309.256	311.259
UL	600.000	600.000	600.000	600.000	600.000	600.000



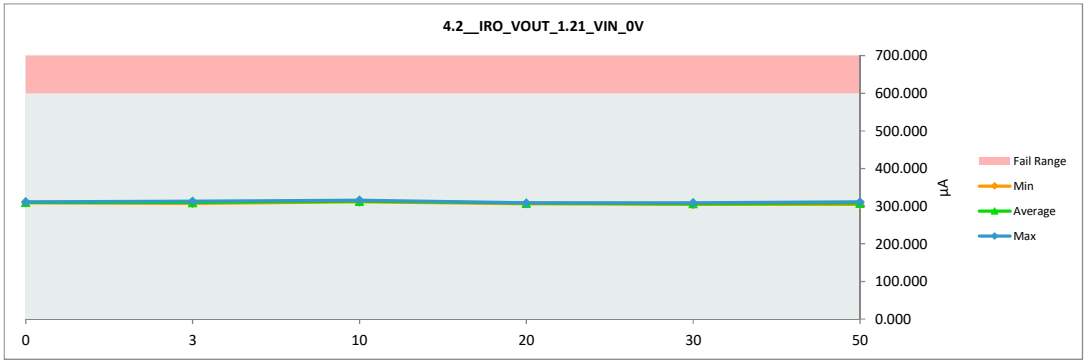
TID LDR Data (Unbiased)
TPS73801-SEP

	4.2__IRO_VOUT_1.21_VIN_0V	
Test Site		
Tester		
Test Number		
Unit	µA	µA
Max Limit	600	600
Min Limit		

Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	309.040	309.255	0.215
0	69	311.210	311.591	0.382
0	70	309.290	309.941	0.652
3	6	313.542	313.017	-0.524
3	7	307.729	307.716	-0.013
3	8	307.401	307.366	-0.034
3	9	310.712	310.731	0.019
3	10	308.493	309.599	1.106
10	16	315.245	316.066	0.822
10	17	311.247	311.946	0.698
10	18	310.448	311.400	0.952
10	19	311.425	312.084	0.659
10	20	311.886	313.387	1.501
20	63	306.552	306.785	0.232
20	64	307.969	308.611	0.642
20	65	306.735	307.558	0.823
20	66	308.251	308.638	0.387
20	67	308.228	308.638	0.410
30	26	304.862	305.699	0.837
30	27	306.096	307.104	1.008
30	28	304.211	304.702	0.491
30	29	307.976	308.993	1.017
30	30	307.026	307.916	0.890
50	36	306.547	305.504	-1.044
50	37	310.775	310.239	-0.537
50	38	311.686	310.988	-0.699
50	39	305.689	304.913	-0.775
50	40	308.996	308.433	-0.563
Max		315.245	316.066	1.501
Average		308.902	309.244	0.341
Min		304.211	304.702	-1.044
Std Dev		2.633	2.716	0.657



	4.2__IRO_VOUT_1.21_VIN_0V					
Test Site						
Tester						
Test Number						
Max Limit	600	µA				
Min Limit		µA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	309.255	307.366	311.400	306.785	304.702	304.913
Average	310.263	309.686	312.977	308.046	306.883	308.015
Max	311.591	313.017	316.067	308.638	308.993	310.988
UL	600.000	600.000	600.000	600.000	600.000	600.000



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